

The background features a technical illustration of an optical system. It shows a light source at the top left, with light rays passing through a series of lenses and mirrors. The rays are depicted as white lines against a blue, semi-transparent background. The overall aesthetic is clean and professional, typical of a scientific or industrial presentation.

Optical Quality Control for Industry: Applicable in Laboratory up to Inline-Inspection

Dr. Josef Frohn
NanoFocus AG
Oberhausen, Ettlingen

founded in 1994

optical surface inspection:
development & production of
3D laser profilometer μ scan[®] &
3D confocal microscope μ surf[®]

main markets:
automotive, micro technology,
medical, forensic, electronics,
printig

> 500 installed systems



NanoFocus AG
HQ
Oberhausen
Germany



NanoFocus
Sales
Ettlingen
Germany

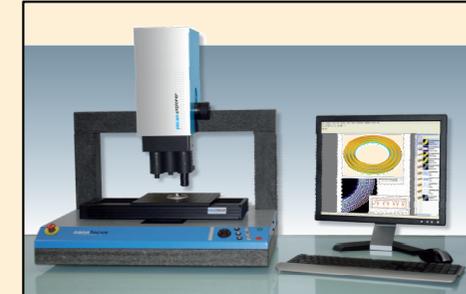
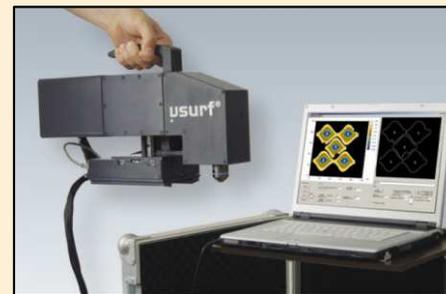


NanoFocus Inc.
Glen Allen, VA USA

Product Range

Standard products

(μ surf explorer, μ surf mobile, μ scan explorer)



Customized systems

(μ surf custom, μ scan custom, μ sprint custom)



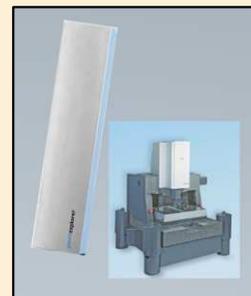
Business solution

(μ surf solar, μ surf cylinder, μ surf blade etc.)



Integration

(μ surf OEM, μ scan OEM, μ sprint OEM)



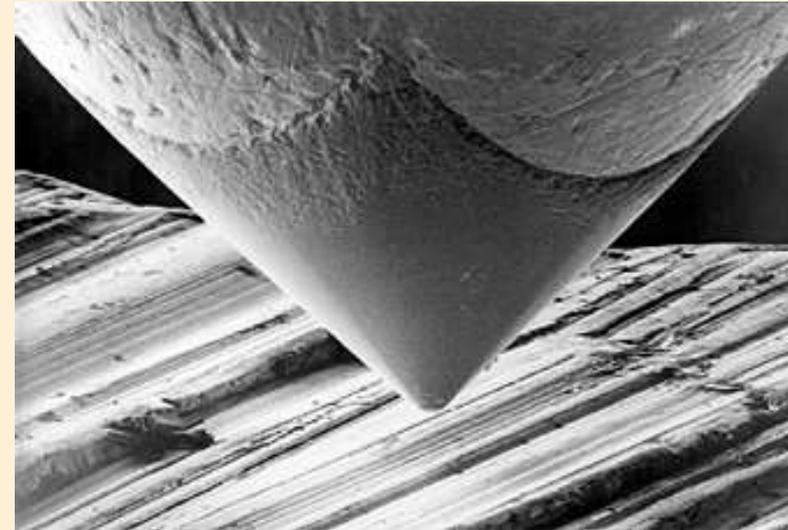
Conventional Surface Measurement



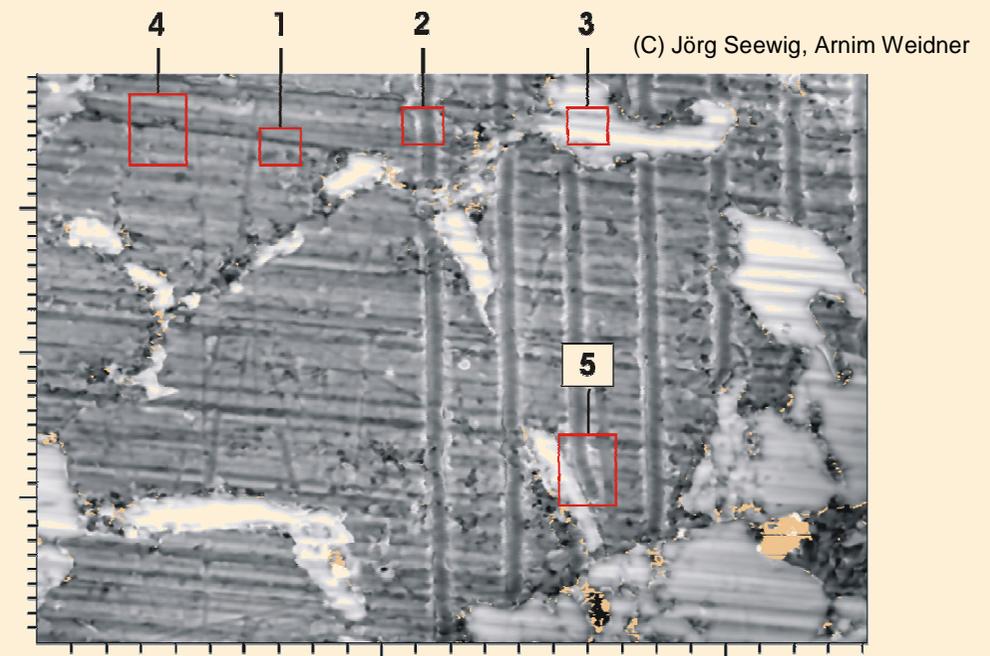
stylus profilometer

according to DIN/ISO standards,
but

- touching, sometimes destructive
- 3D measuring awkward to do
- fragile setup
- slow
- wear of probe (costs!)



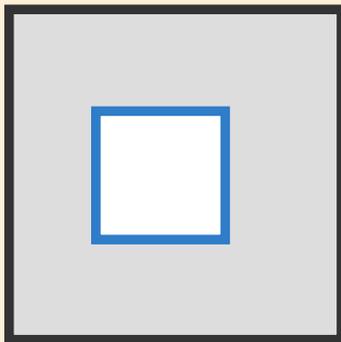
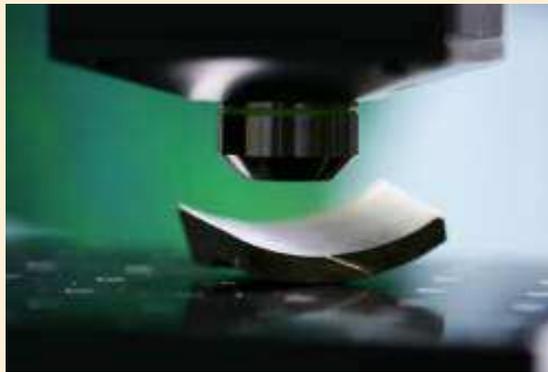
diamond tip on sheet metal (Dr. Hillmann, PTB)



Product Categories

μsurf®

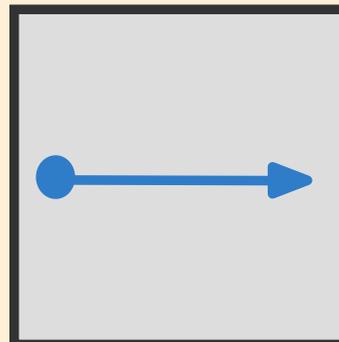
3D-Microscopy



- 3D-Structure
- Wear
- Tribology

μscan®

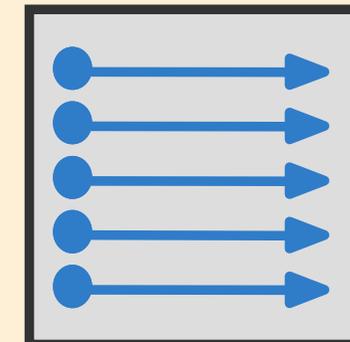
2D-Profilometry



- 2D-Shape
- Roughness

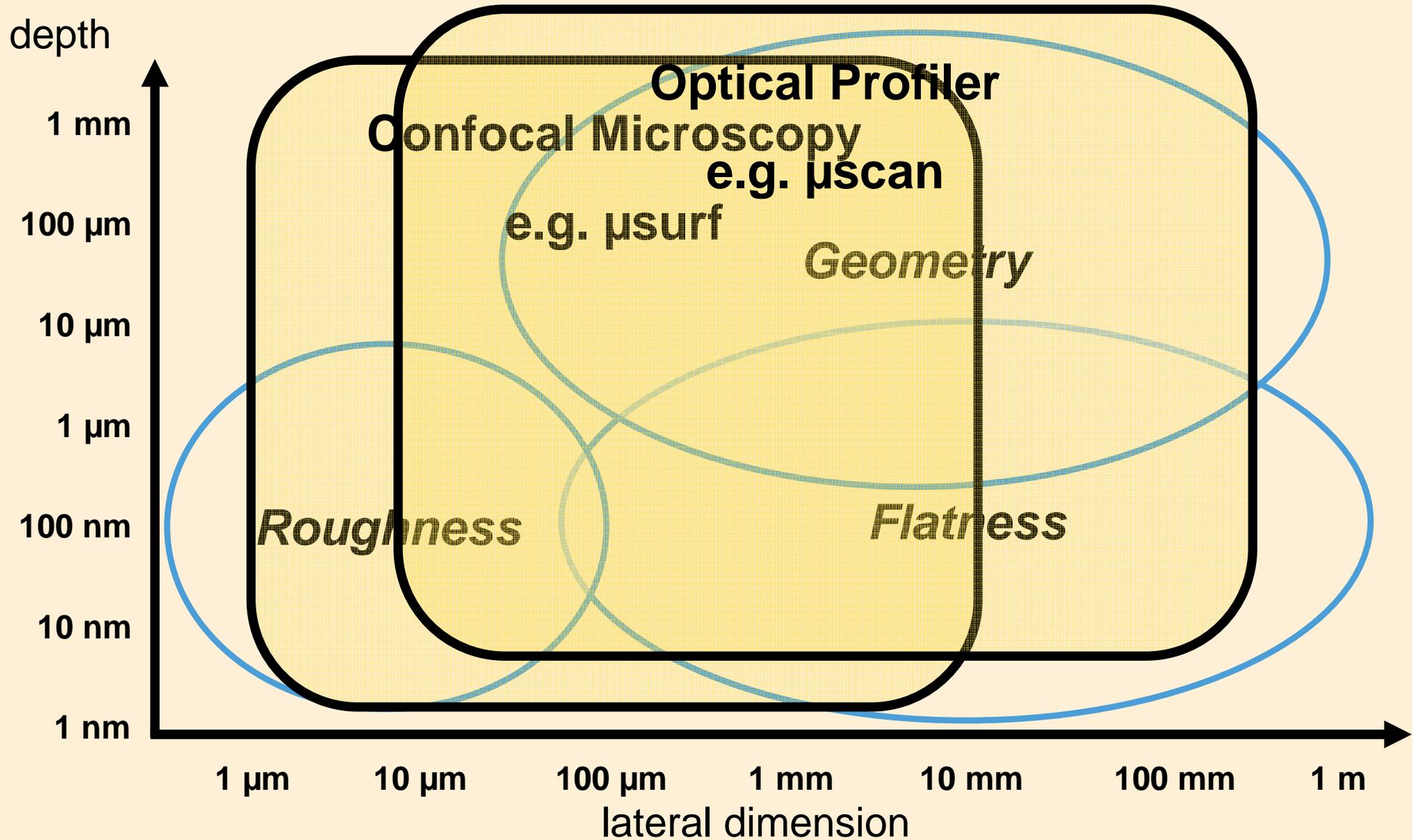
μsprint®

3D-Profilometry

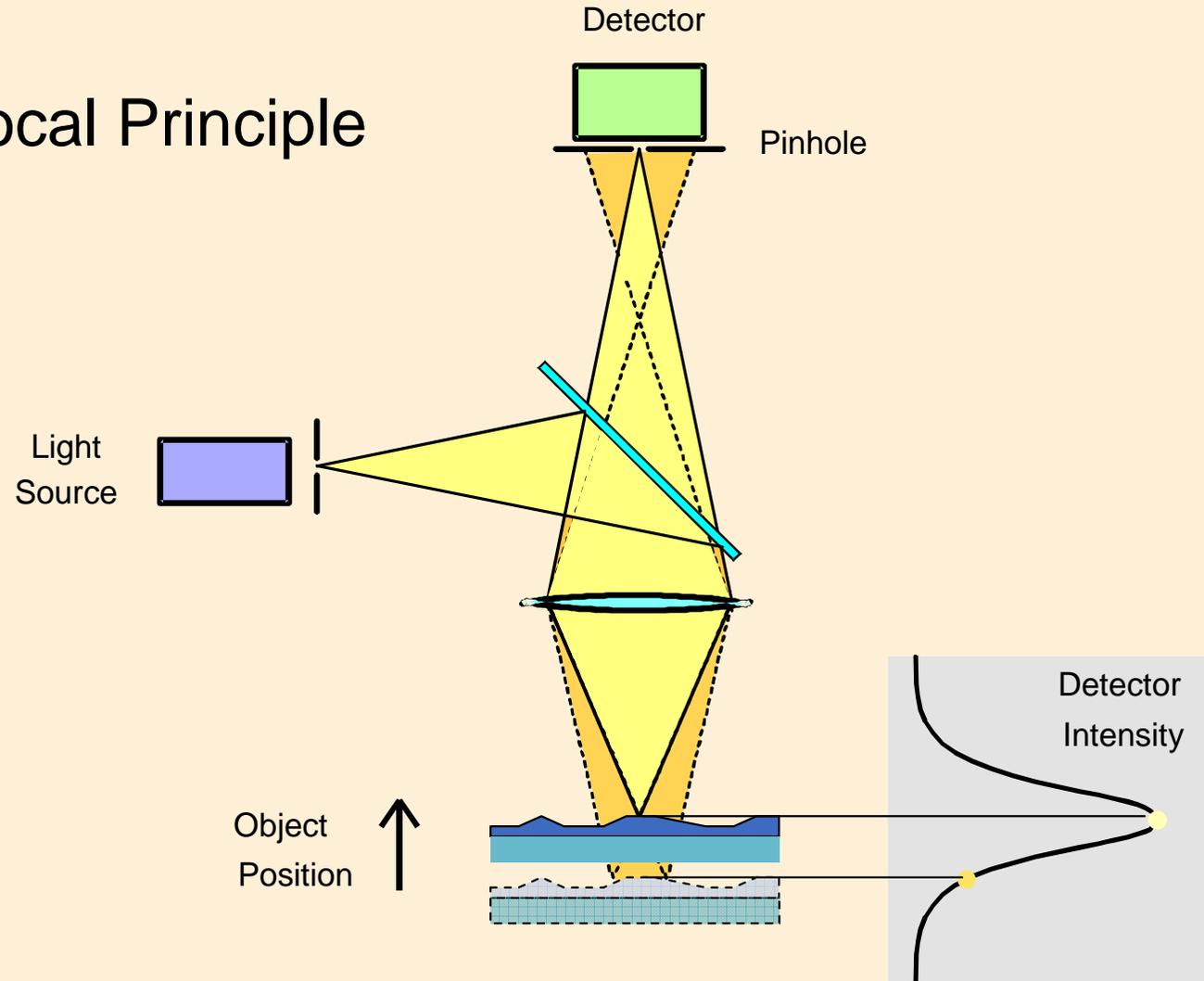


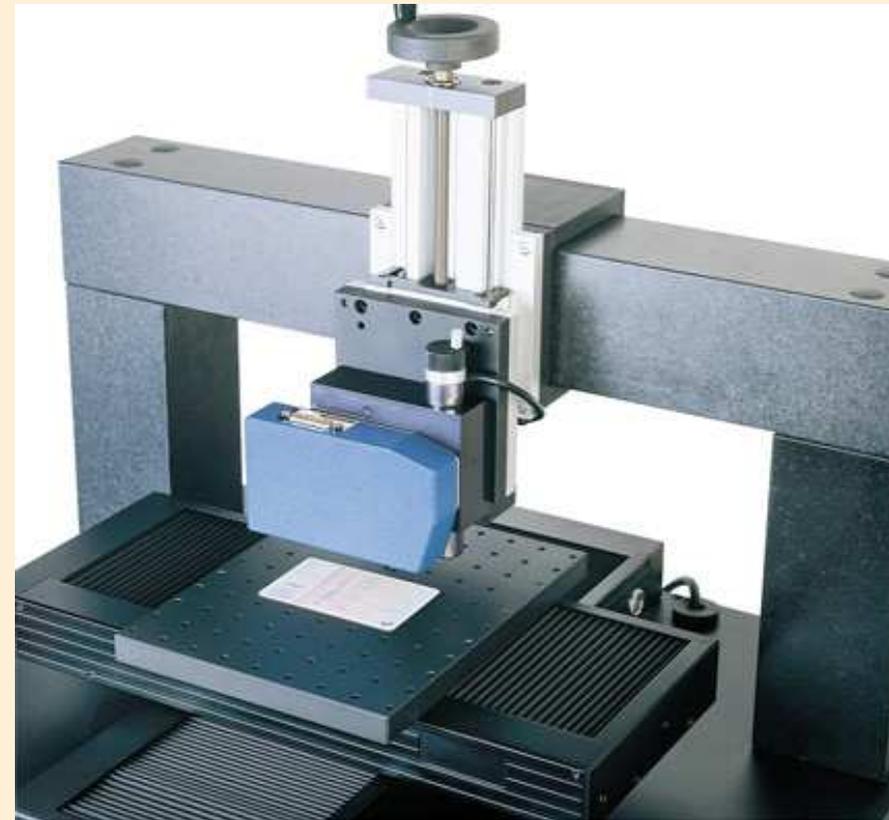
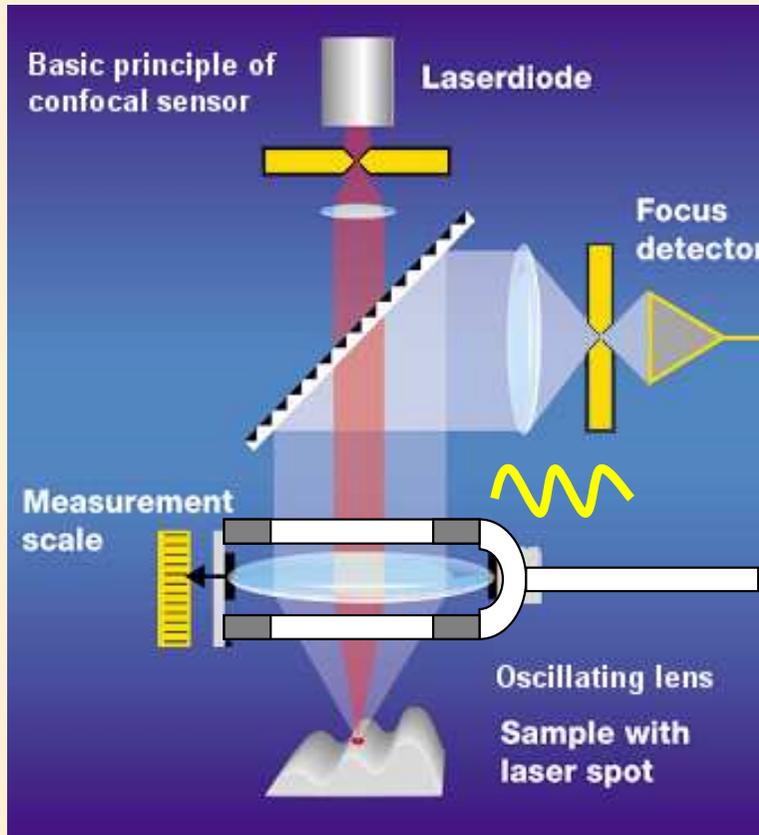
- 3D-Shape
- Defects
- Production Control

Range of Application



► Confocal Principle



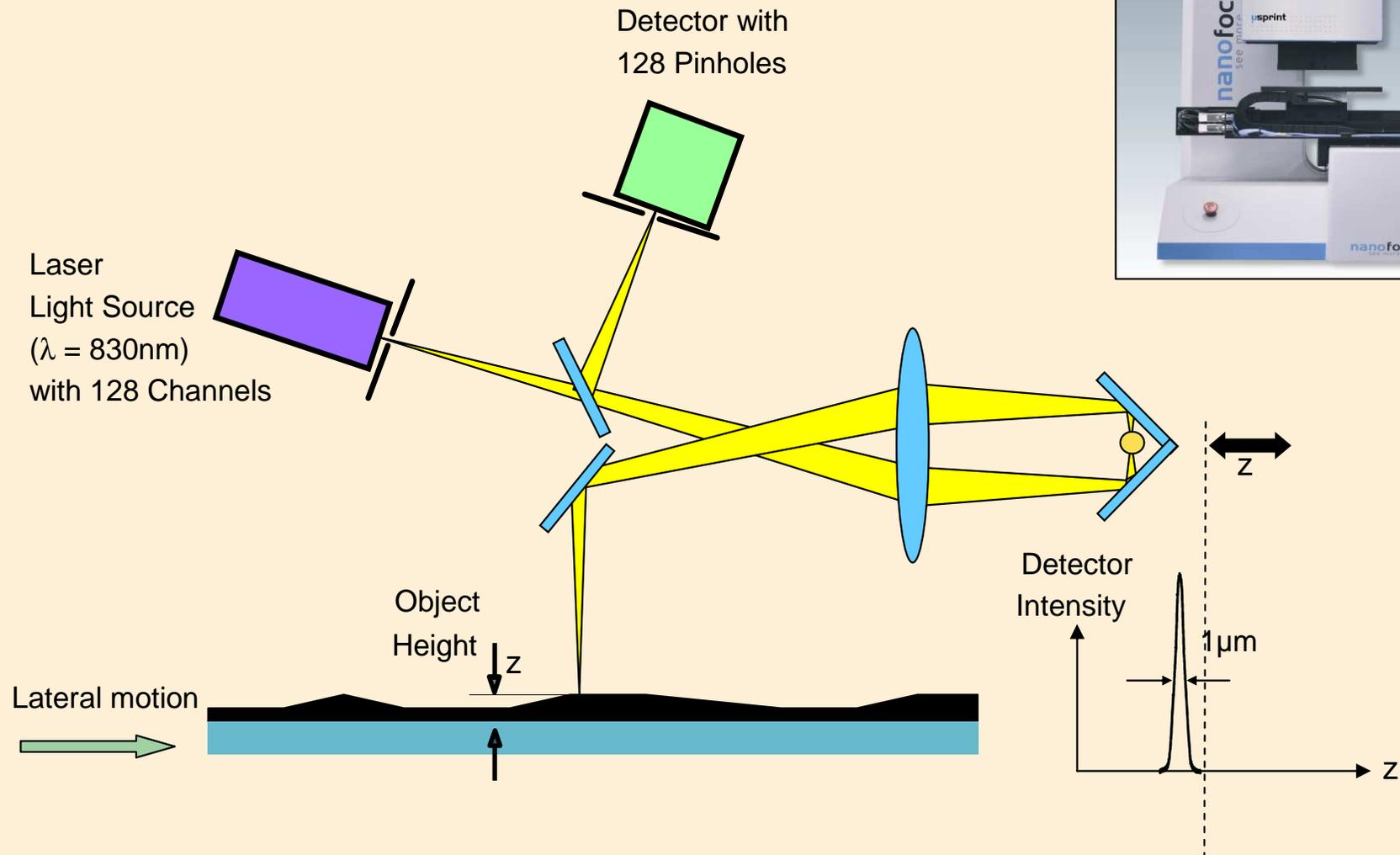


Confocal Point Sensor

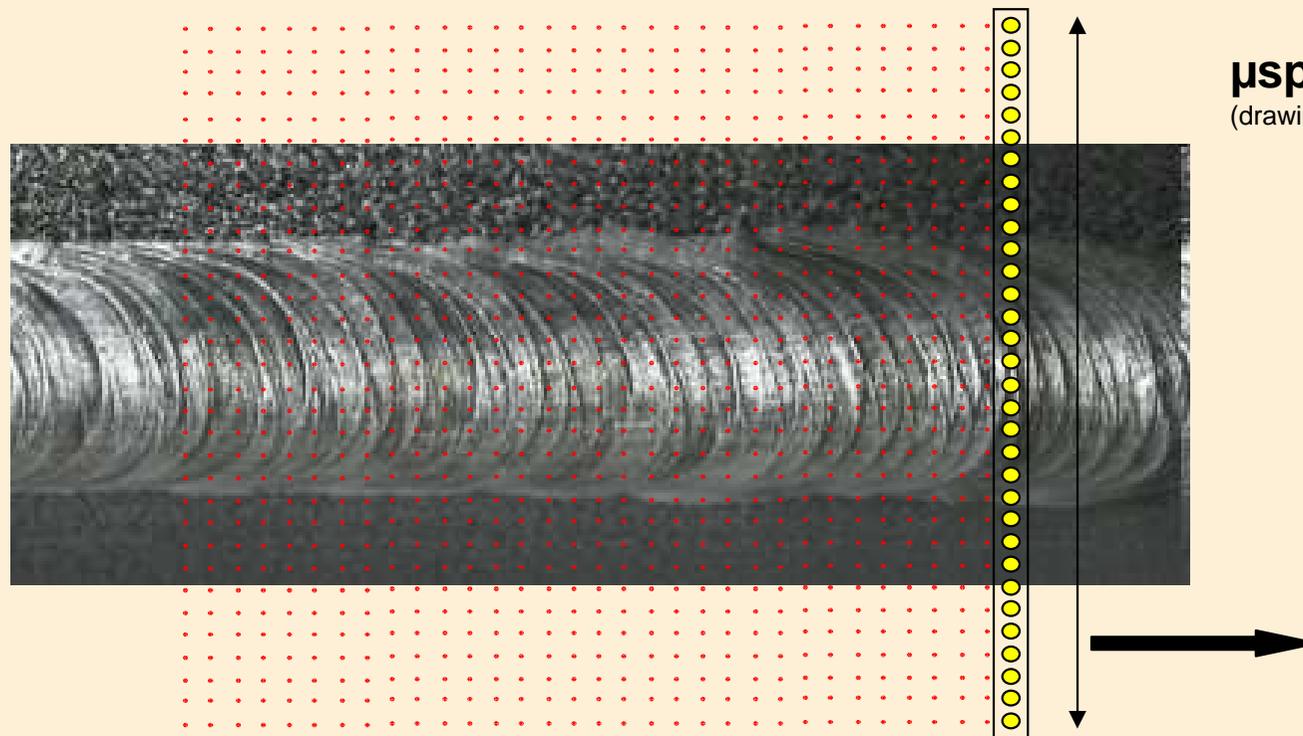
Scanning Profilometer μ scan with offset camera

Scanning by means of multi profile measurements with point sensors:
autofocus, chromatic whitelight, confocal point, holographic

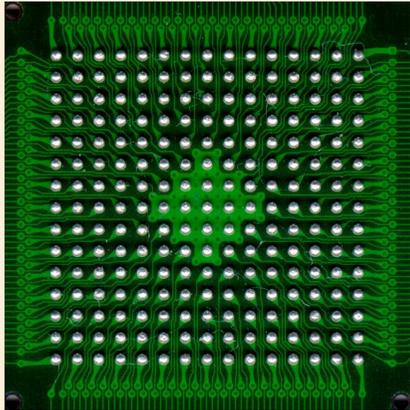
Technology μ sprint



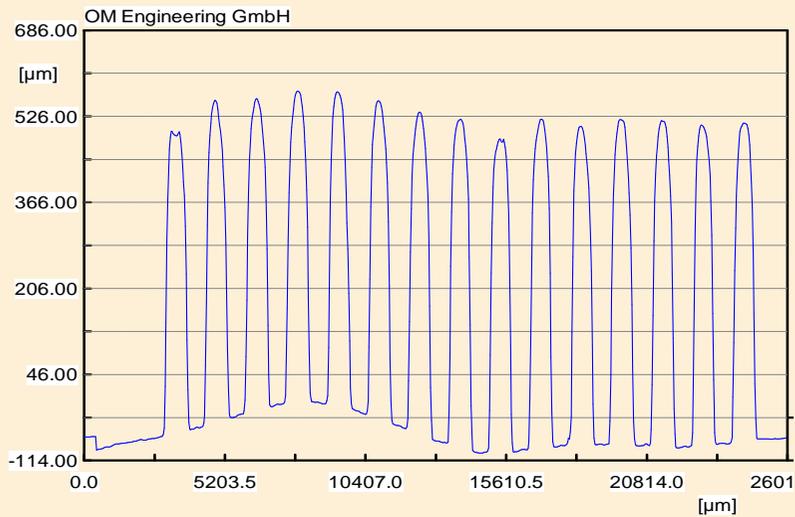
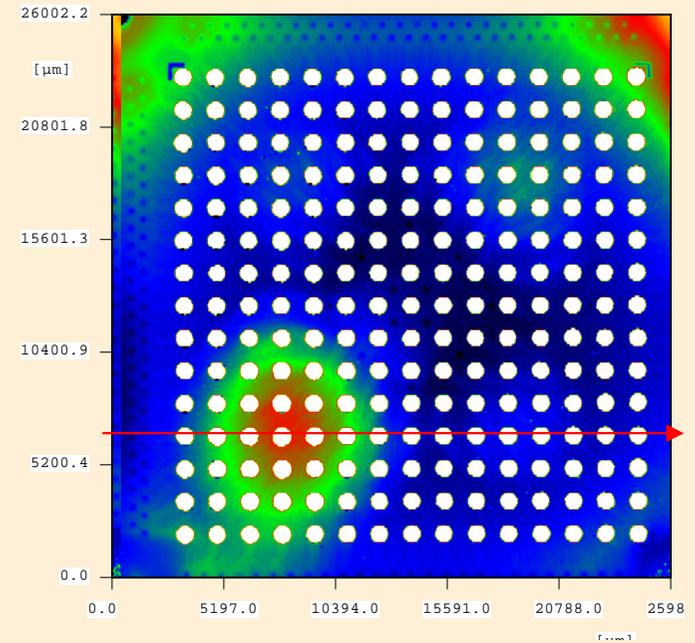
- ▶ 128 parallel channels
- ▶ scanning speed 54mm/s
- ▶ spot diameter 1μm



μsprint Scanning Principle
(drawing not true to scale)

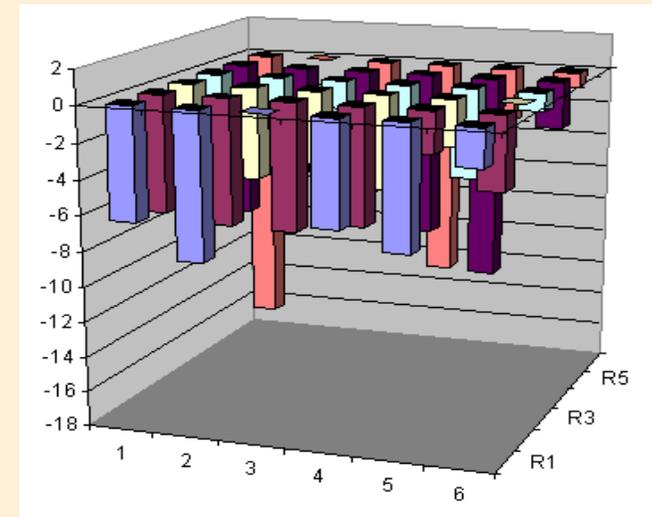


Warpage

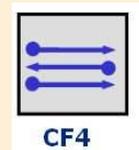
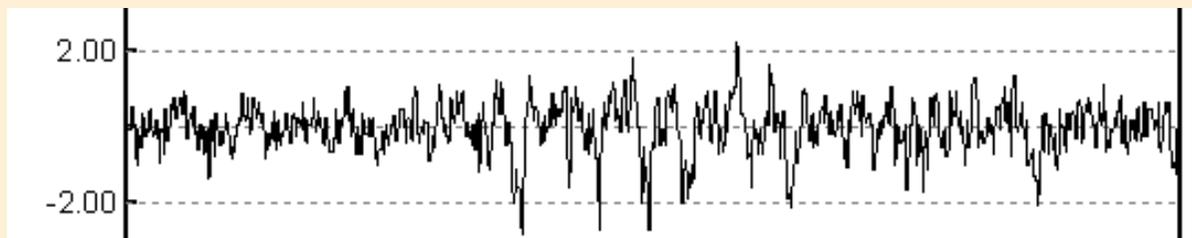
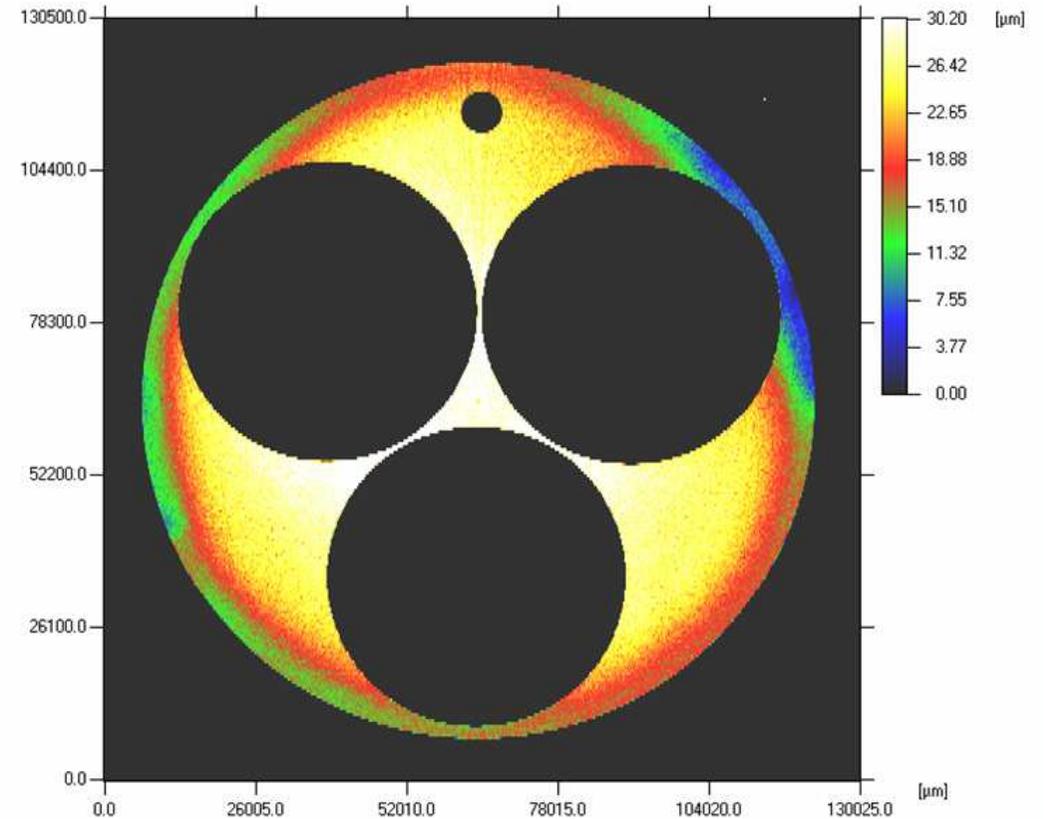
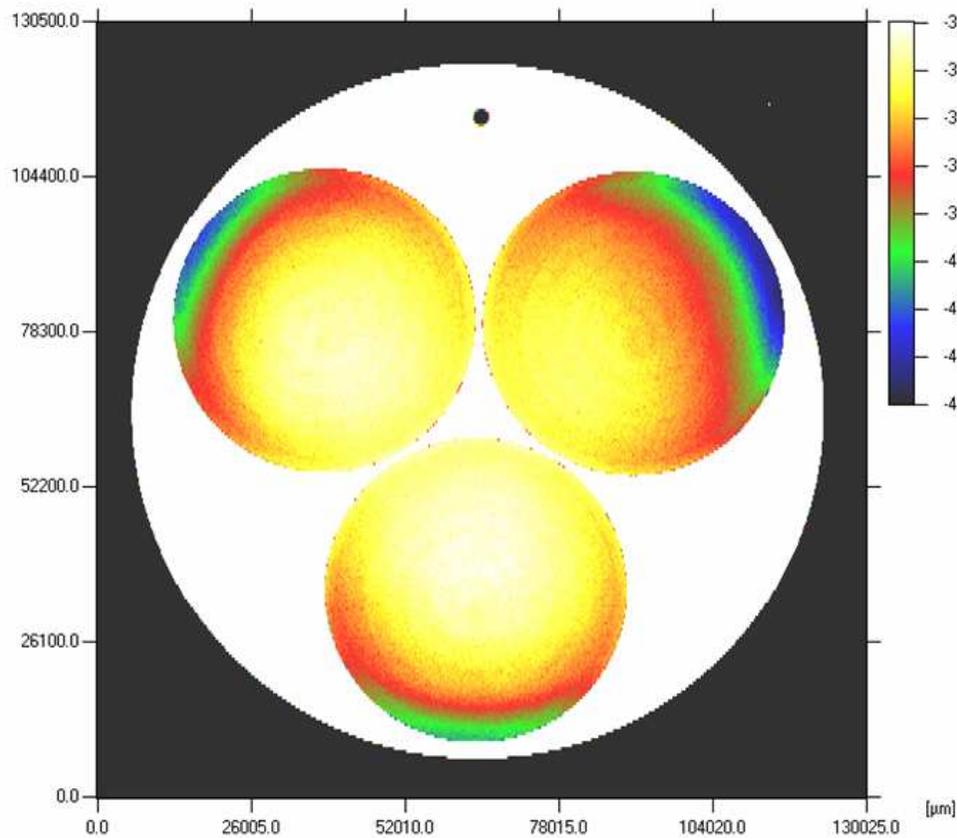


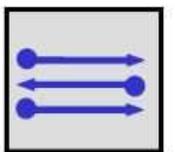
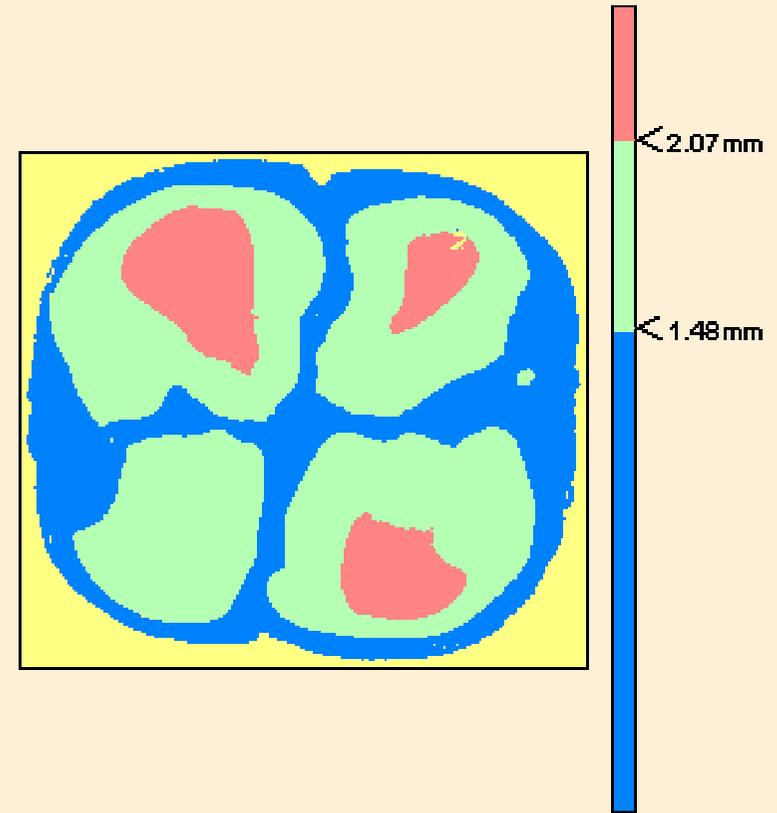
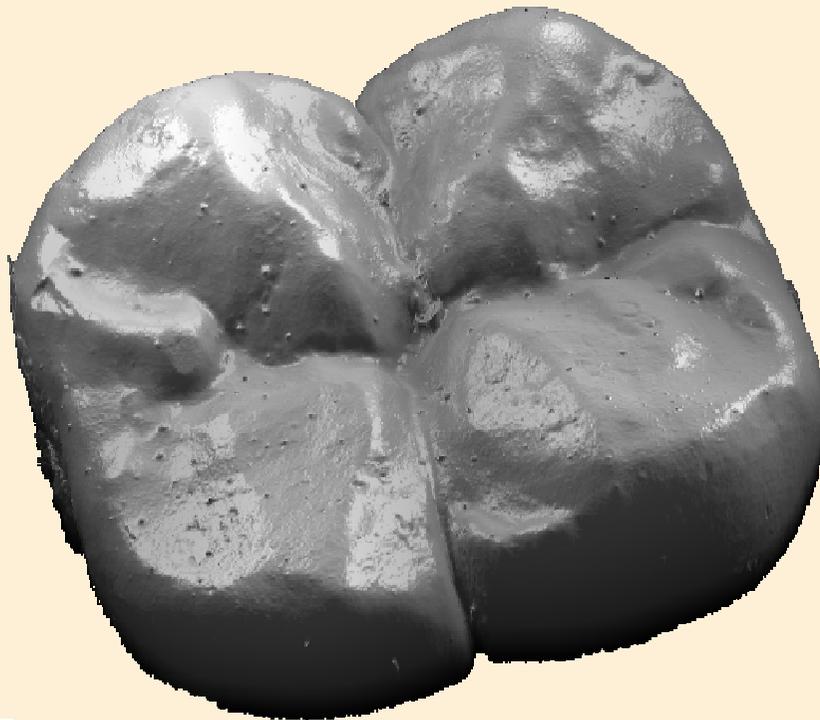
2D Profile

Co-planarity



Wafer Carrier



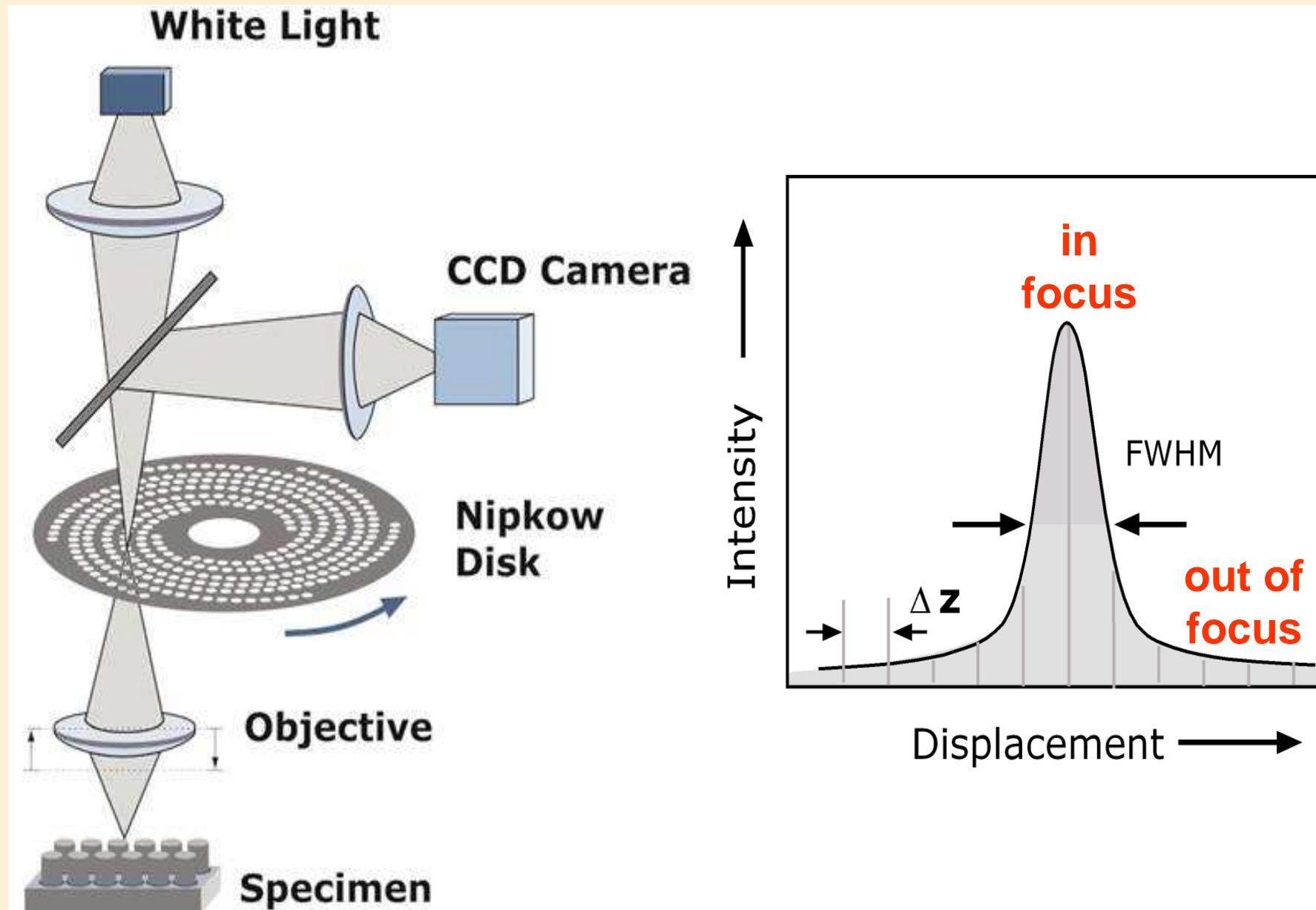


CF4

evaluation of wear

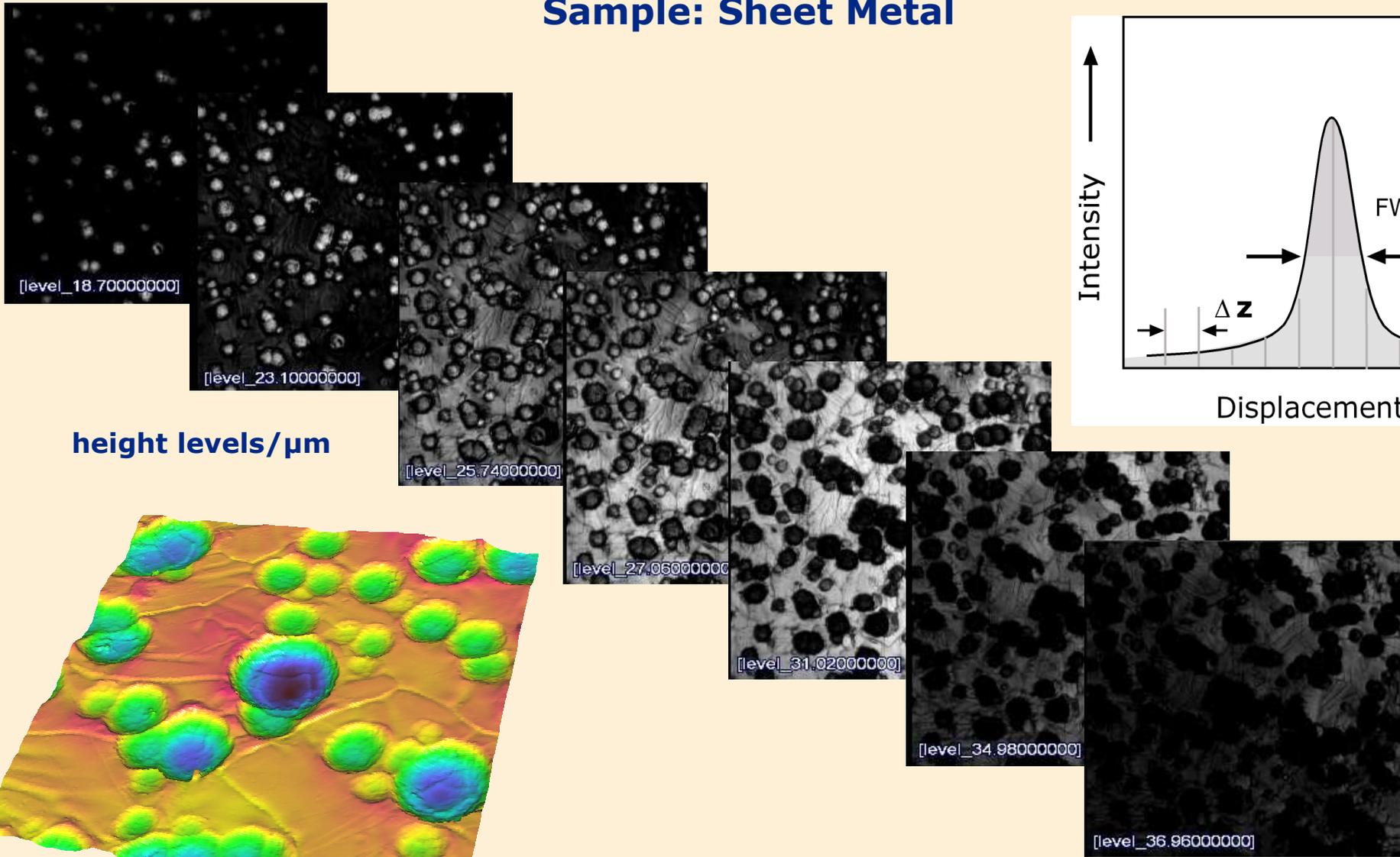
	■	■	■
Area (%)	33.6	53.3	13
Volume of material (%)	92.6	36.5	4.66
Mean thickness of material (mm)	1.37	0.213	0.0193

Confocal Principle

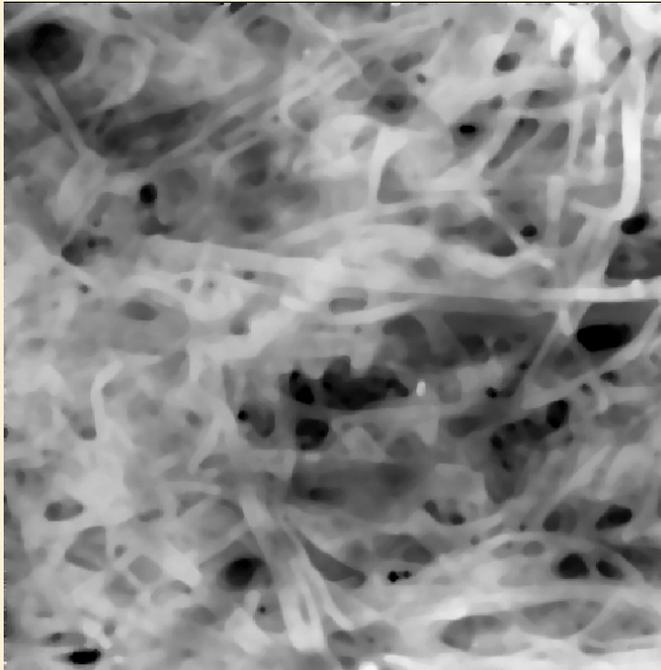


Confocal Imaging Sequence

Sample: Sheet Metal



Topo – reflection – color



height - CFM

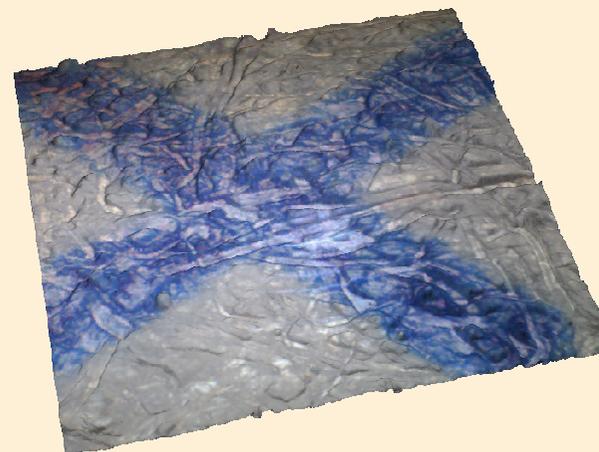


reflection - CFM

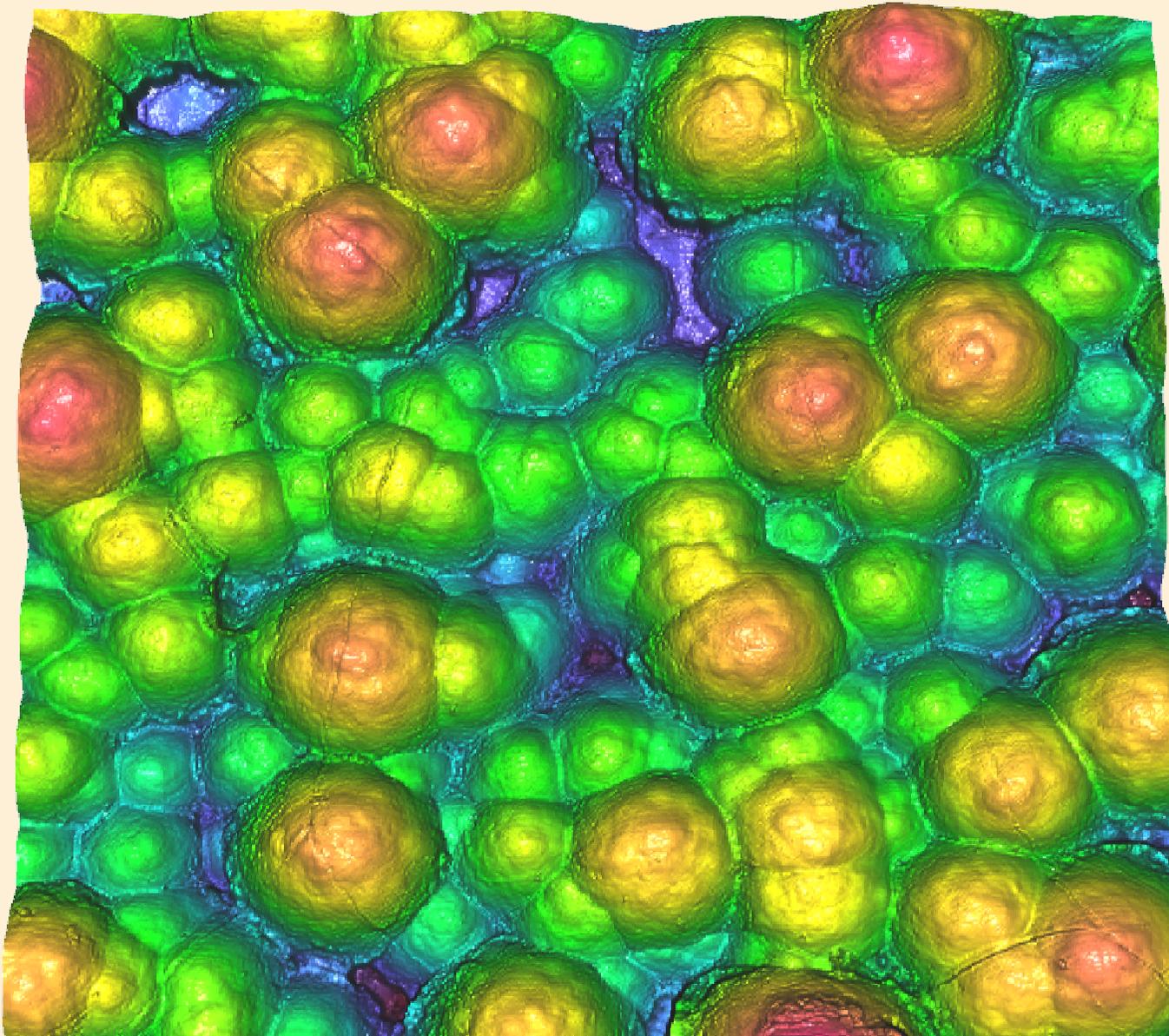


reflection - brightfield

800S



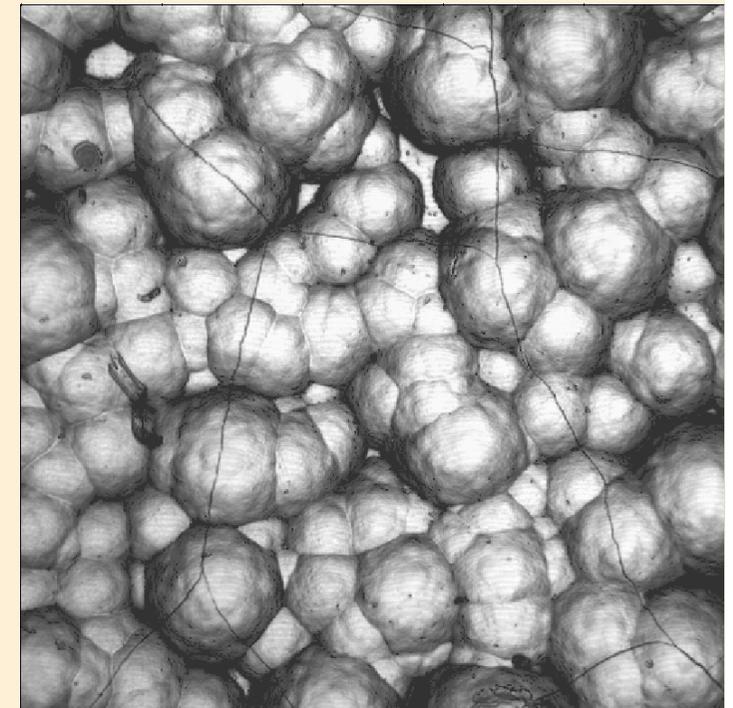
Result: Steel Production Roll



Topocrome

160S / $\Delta Z=13\mu\text{m}$

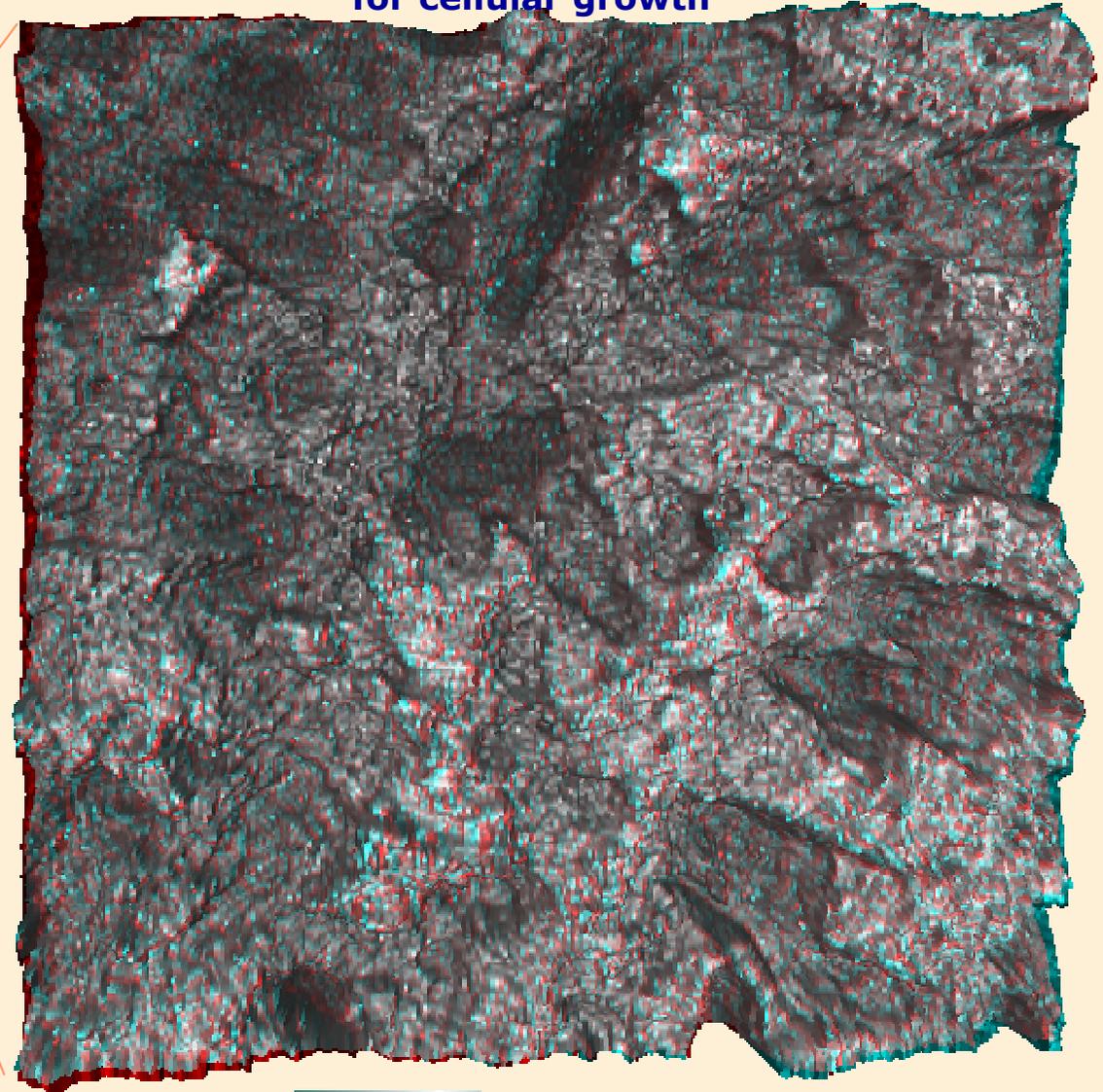
Reflection



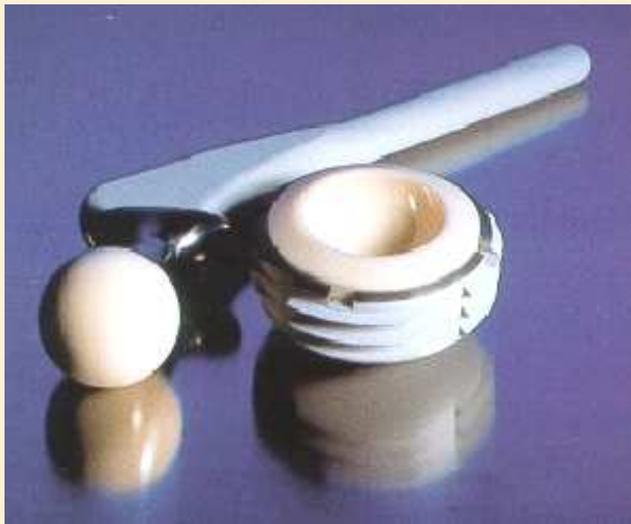
Dental Implants



optimized surface structure
for cellular growth



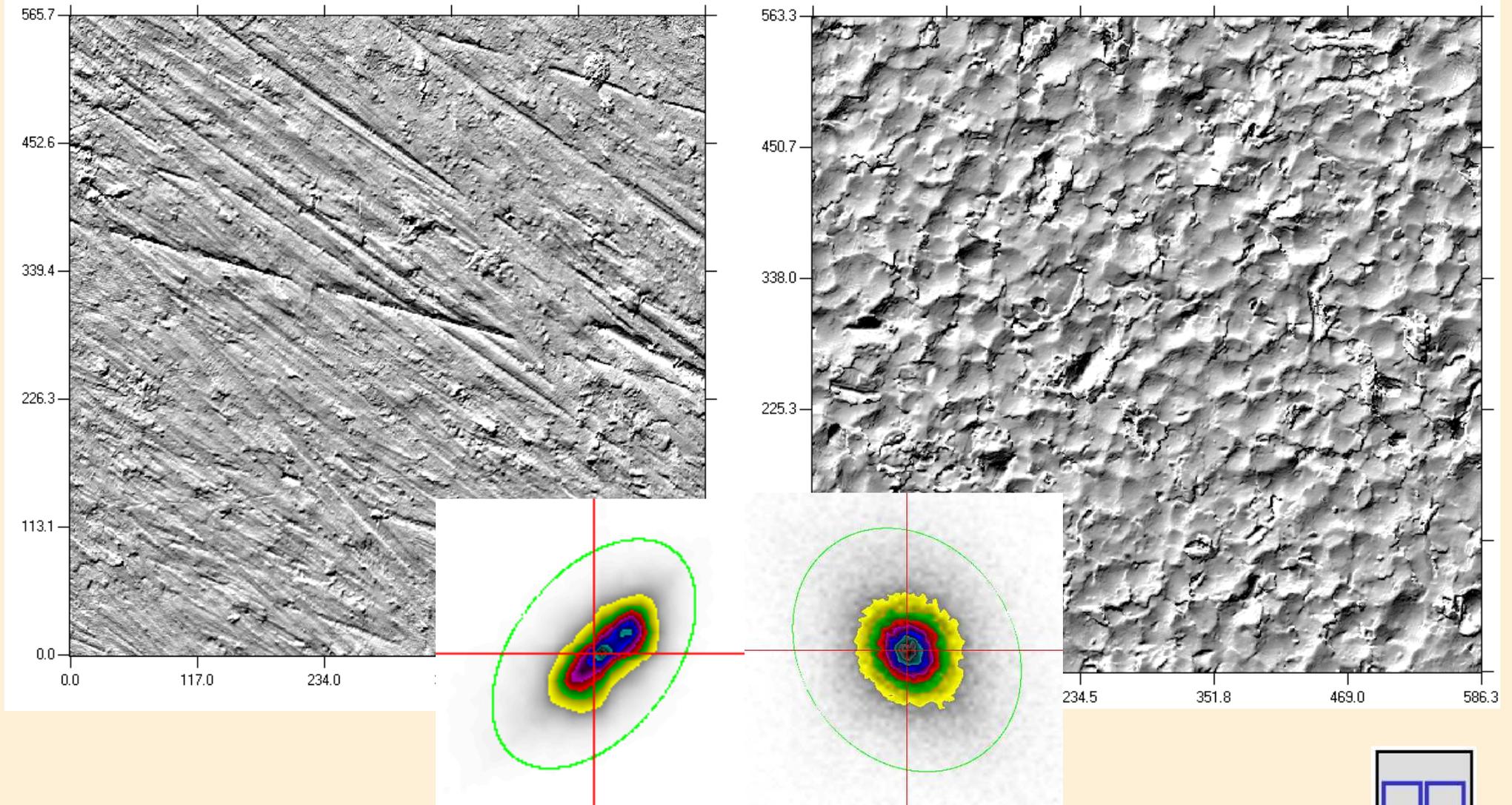
Artificial hip joints



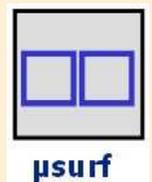
3D

320 x 320 μm^2

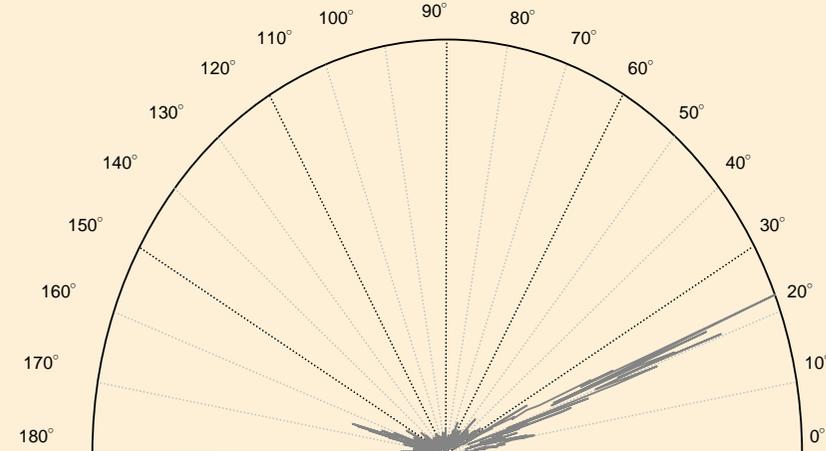
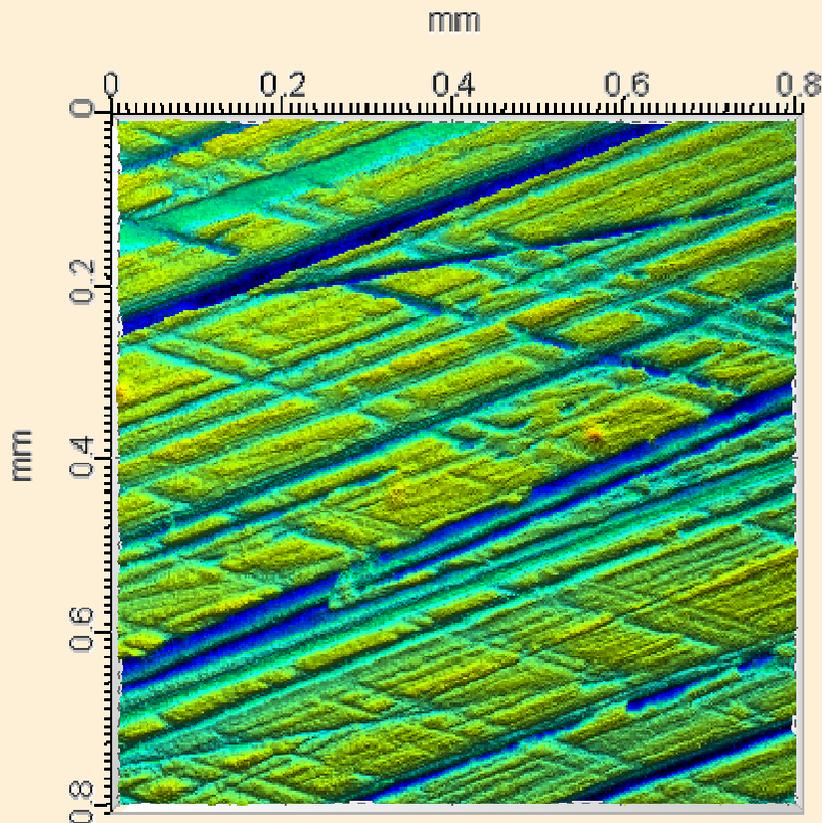
Application: Implants



Roughness Gradient Distribution



► evaluation of texturing direction



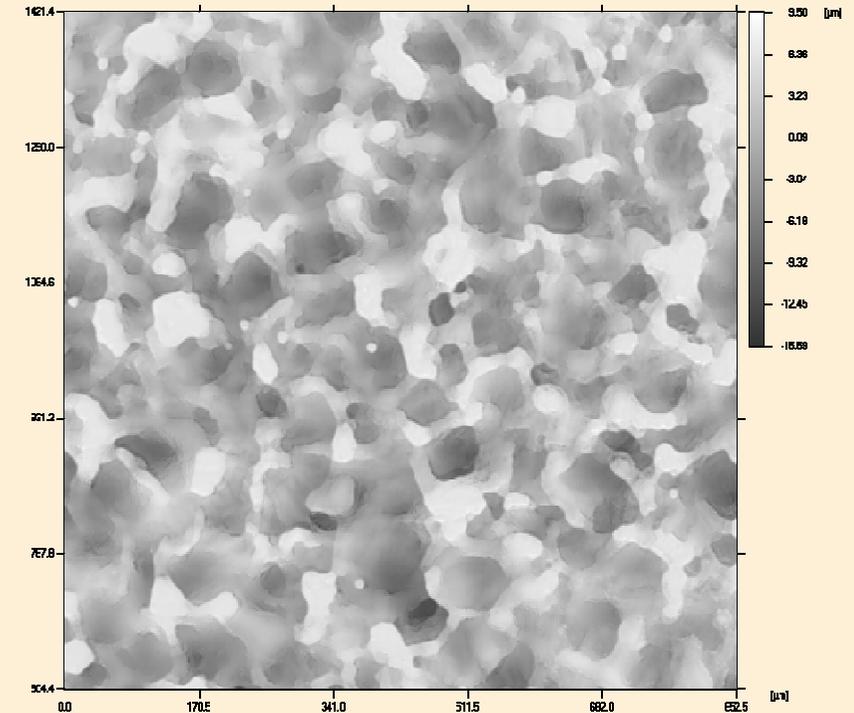
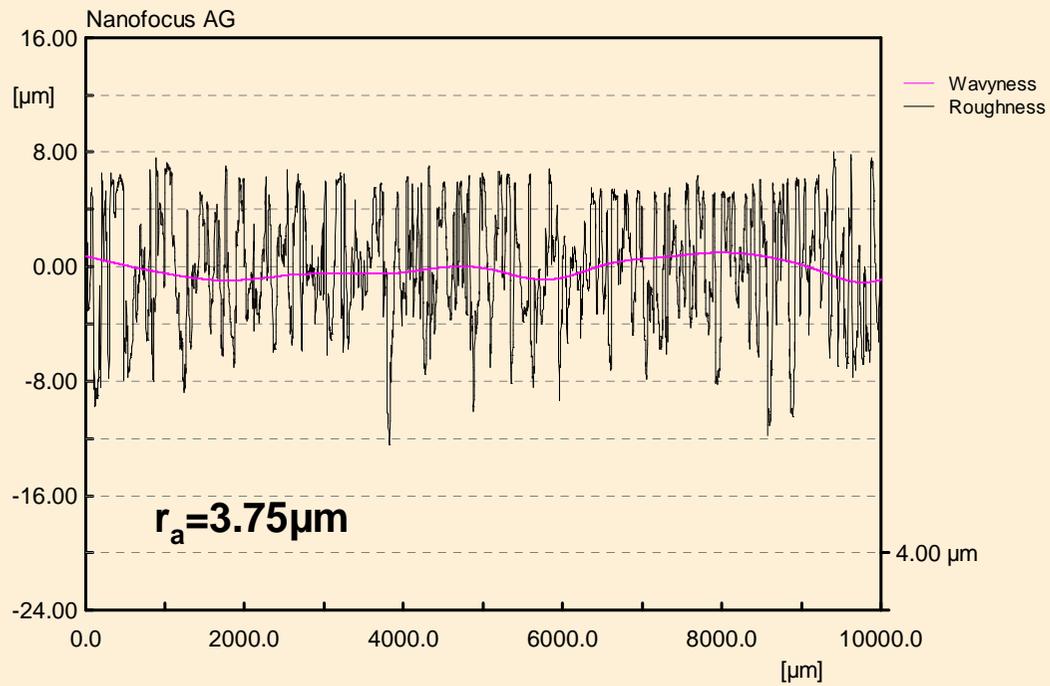
Isotropie: 3.94 %
Erste Richtung: 22.5°
Zweite Richtung: 17.1°

ISO 25178			
Raum-Parameter			
Str	0.0394		Textur-Aussehensverhältnis der Oberfläche
Std	22.5	°	Textur-Richtung der Oberfläche

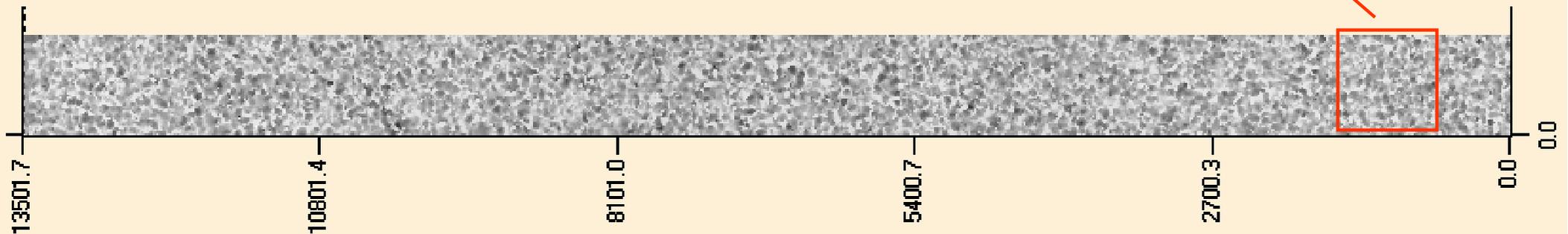
- spatial parameter Str describes the isotropy of the surface
 - Str close to 1: isotrope
 - Str close to 0: non isotrope

- spatial parameter Std describes preferred direction in case of non isotropic surfaces

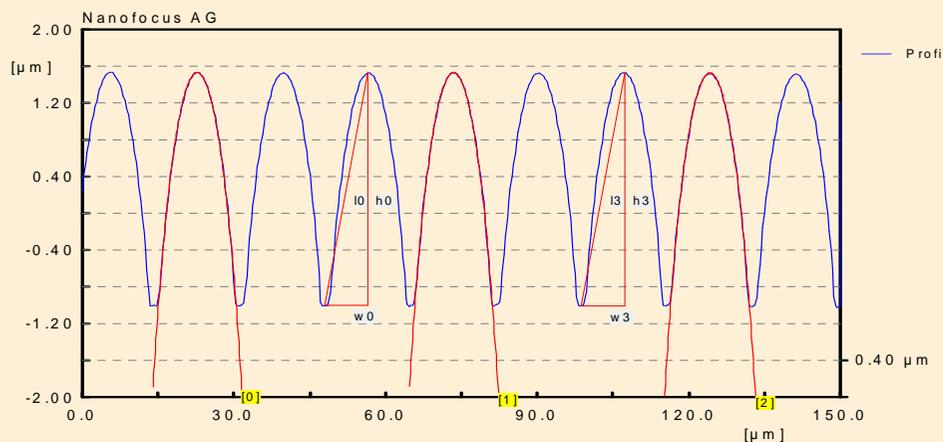
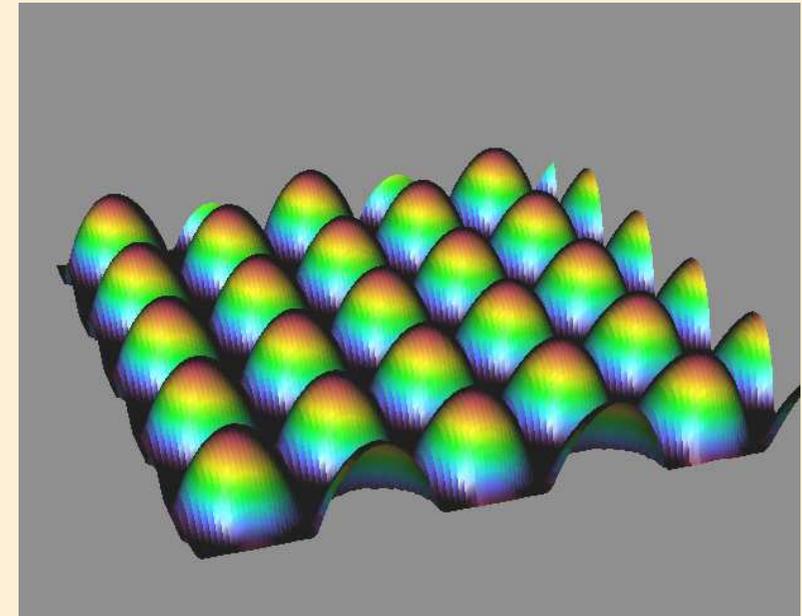
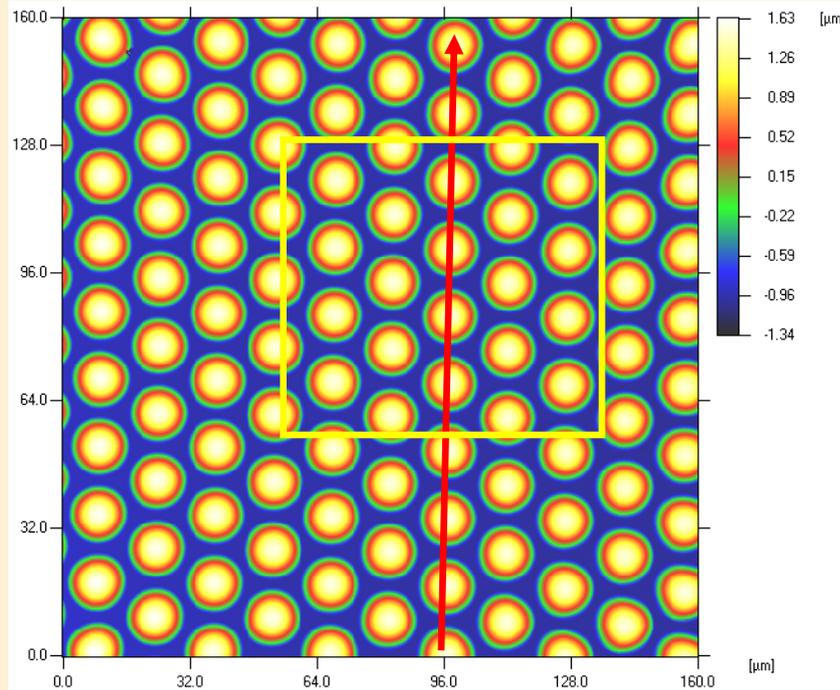
EDT: μ surf mobile 1 x 16



μ surf mobile on a roll, 800S, 1x16 stitching: 1mm x 13mm x 25 μm



Microlens Array



Profile values

Radius (0) = 12,94 μm
 Radius (1) = 12,91 μm
 Radius (2) = 13,30 μm

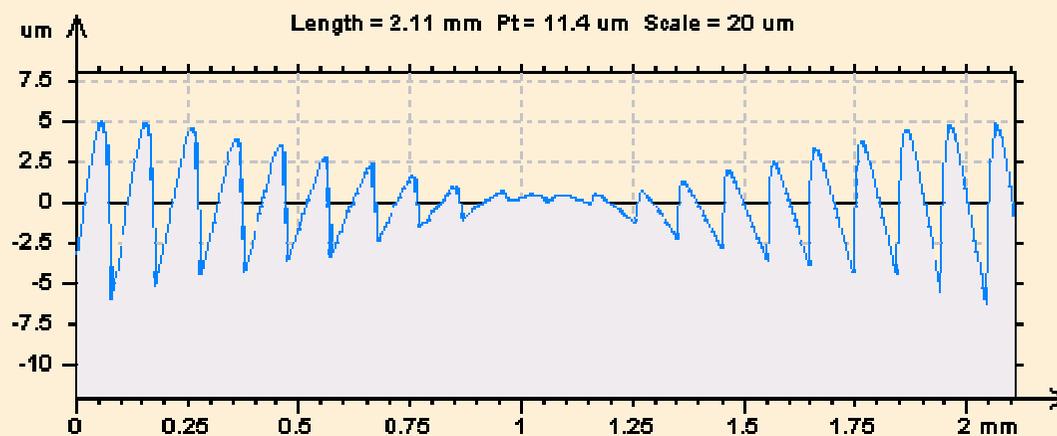
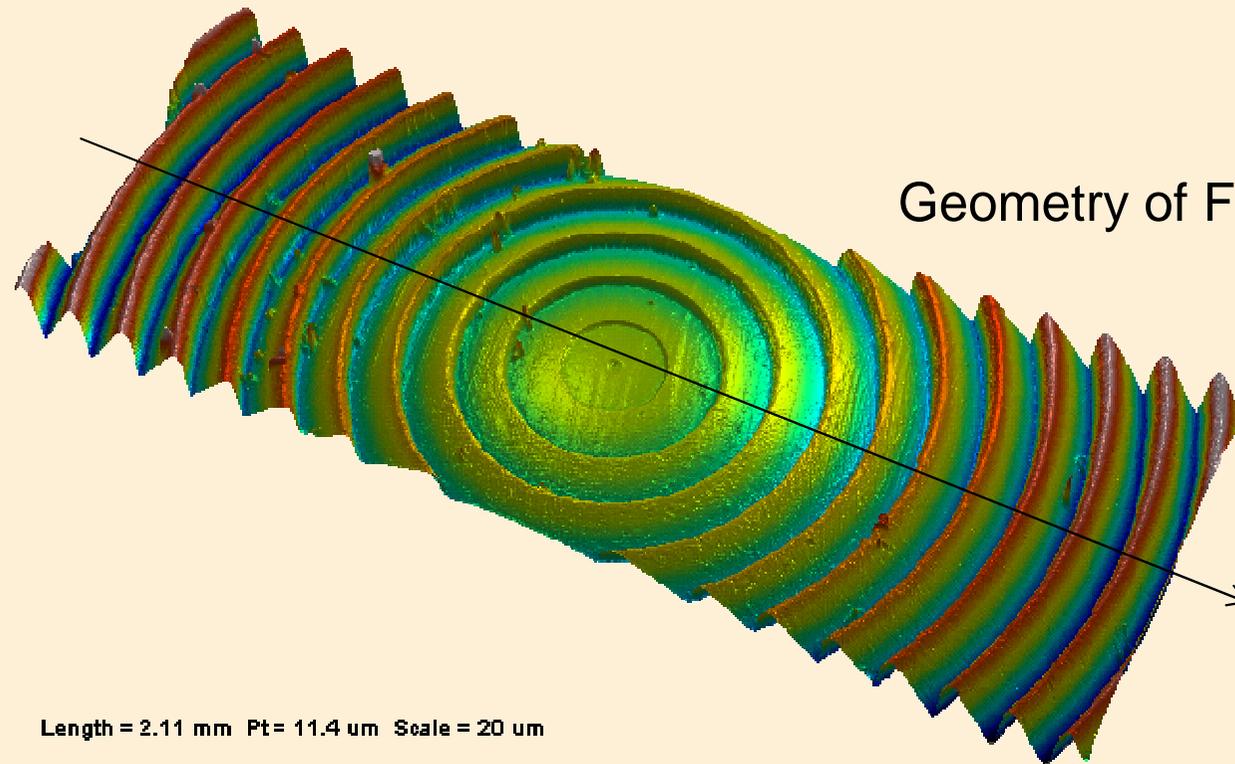
Form 0

Width w_0 = 8,57 μm
 Height h_0 = 2,53 μm
 Length l_0 = 8,94 μm
 Angle = 16,44°

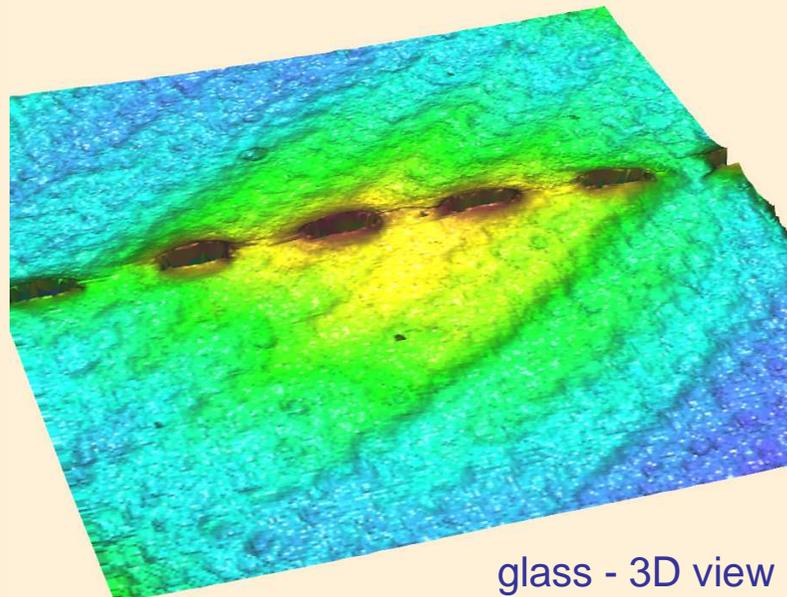
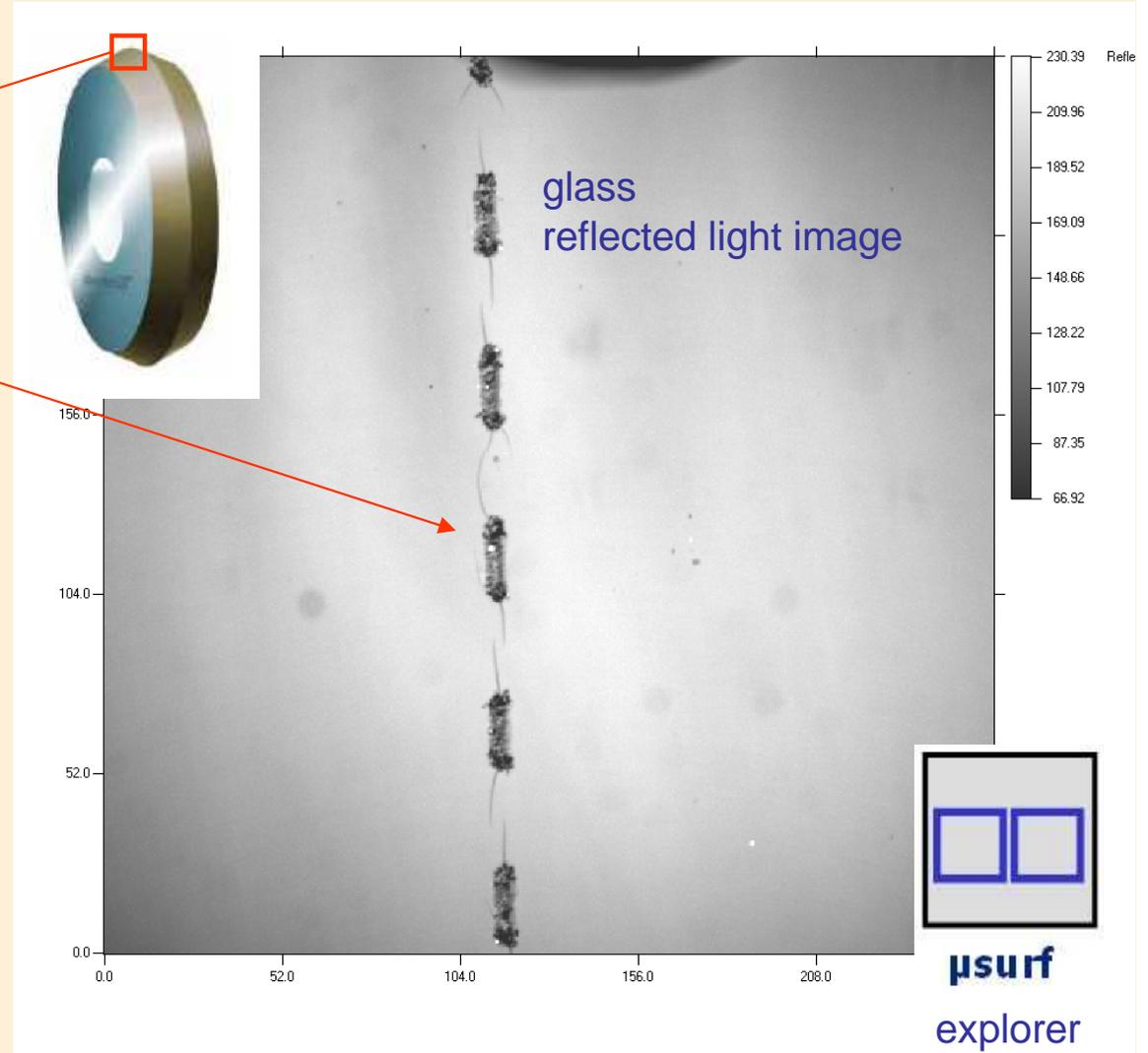
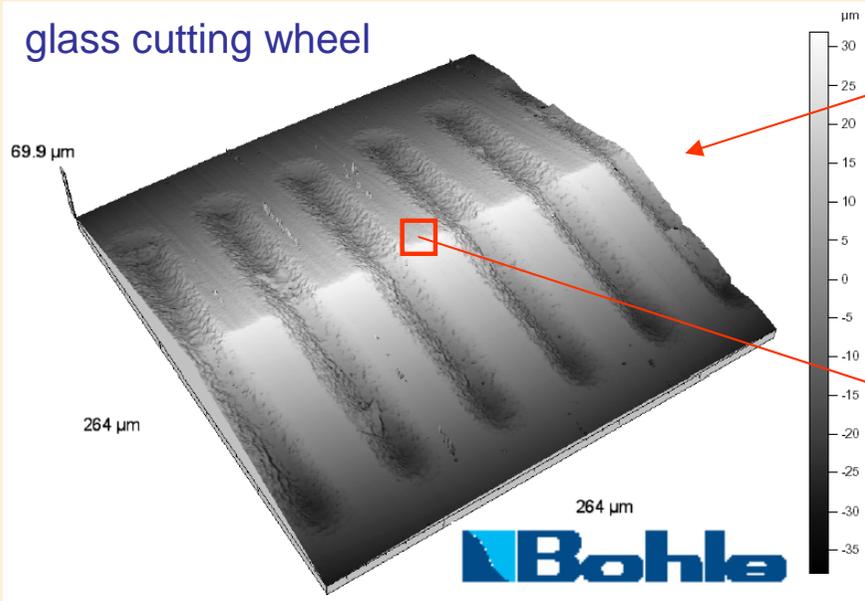
Form 3

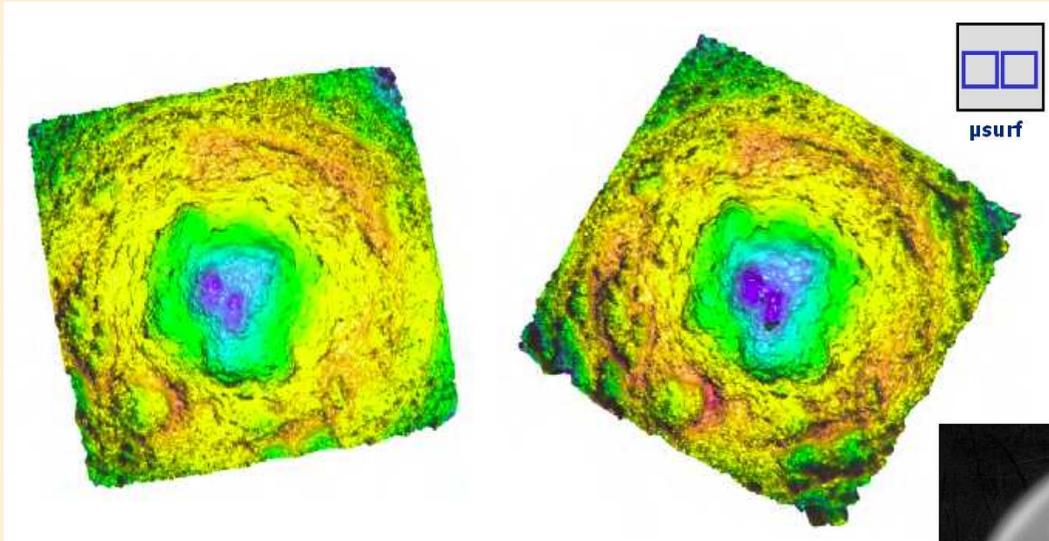
Width w_3 = 8,86 μm
 Height h_3 = 2,53 μm
 Length l_3 = 9,21 μm
 Angle = 15,94°

Measuring task: concentrator cells

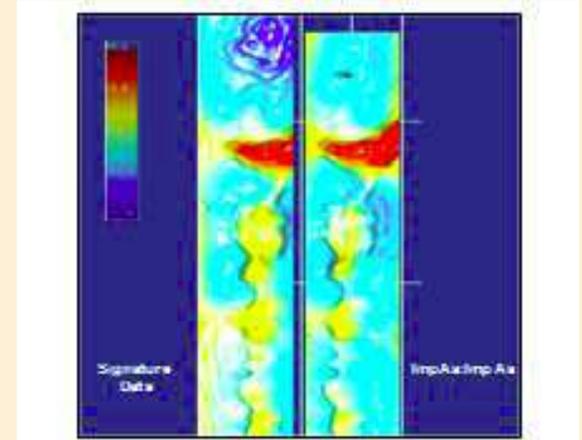
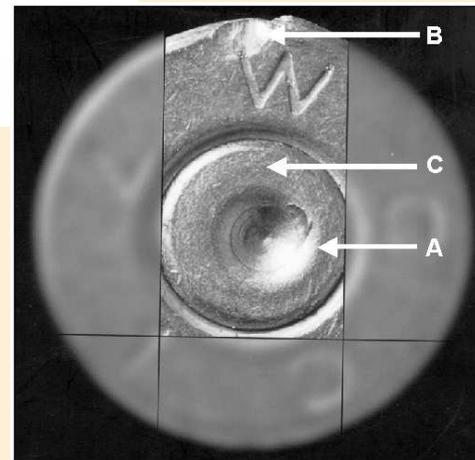


Laser Machining

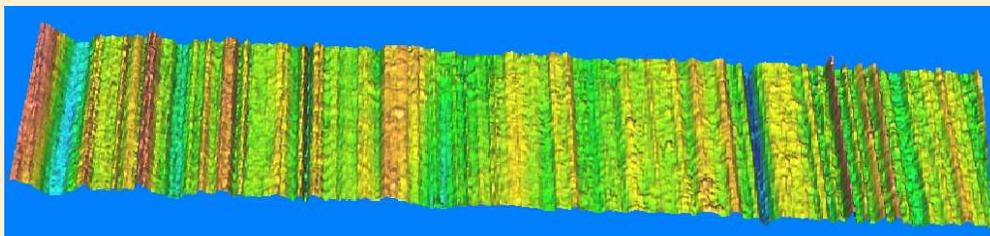




bulet casing - firing pin impression



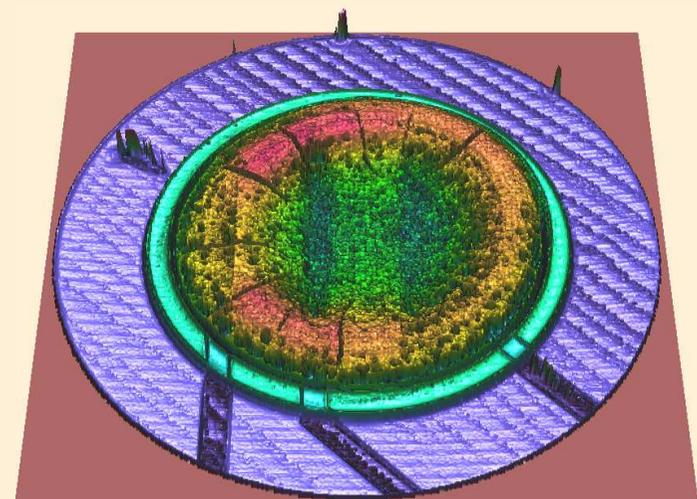
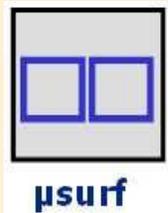
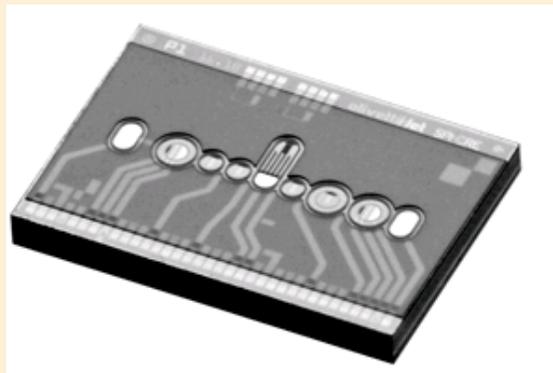
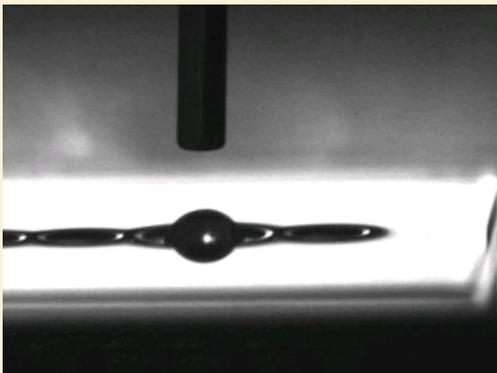
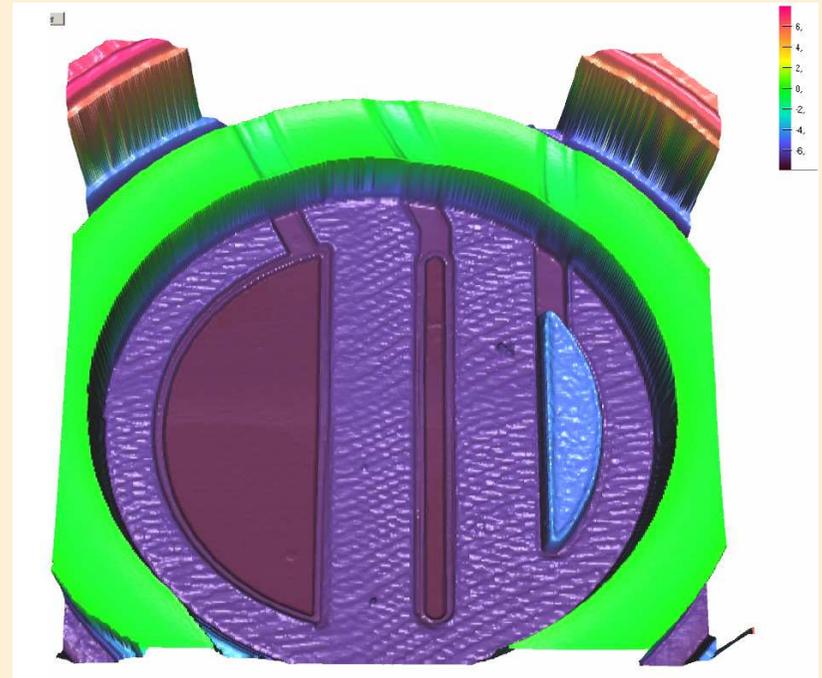
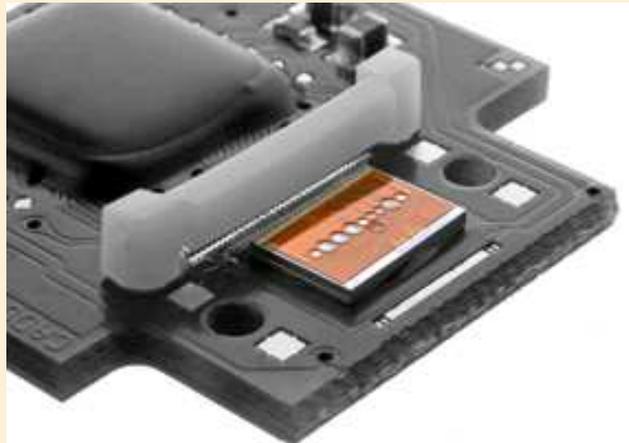
Ballistics Identification
BULLETTRAX™-3D
3D Bullet Acquisition Unit

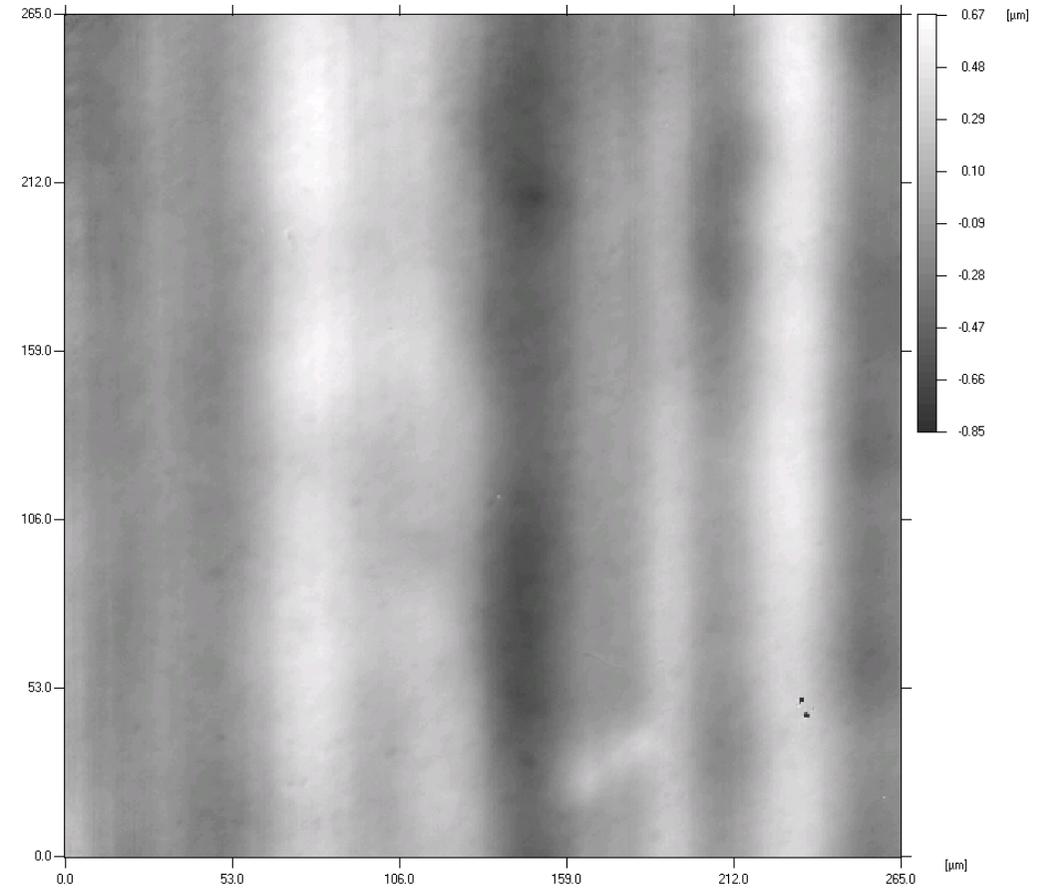
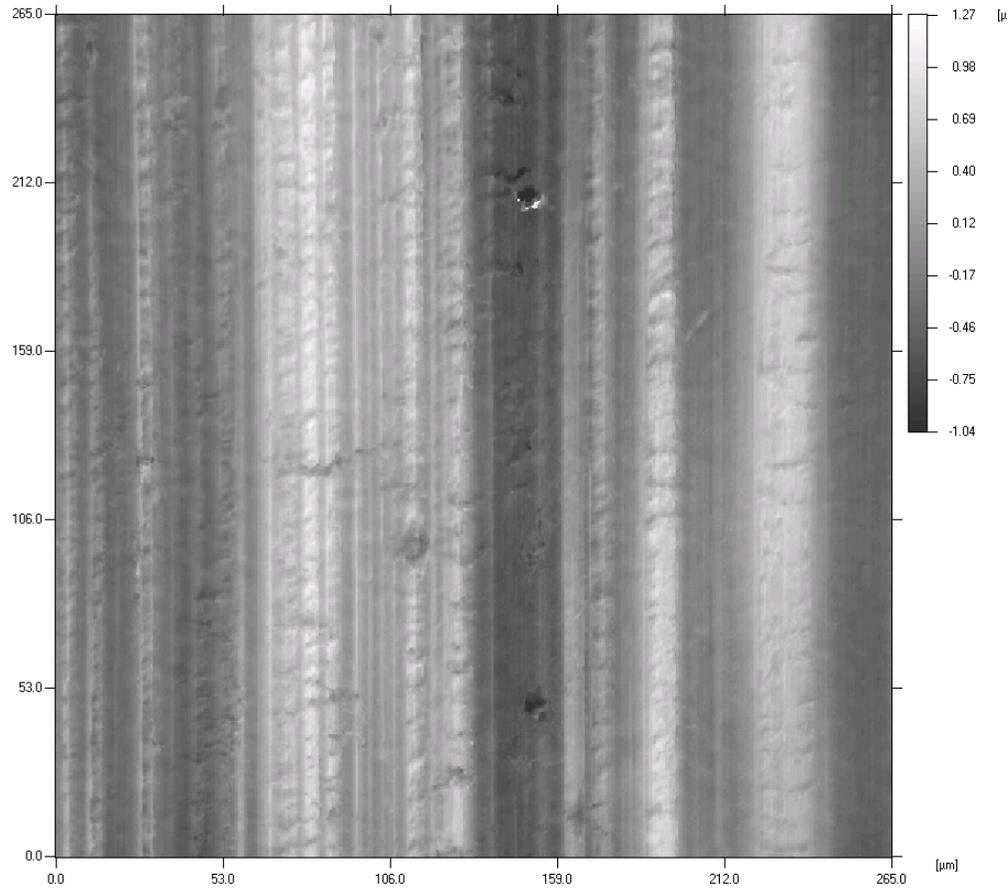


bolt cutter



Micro Systems



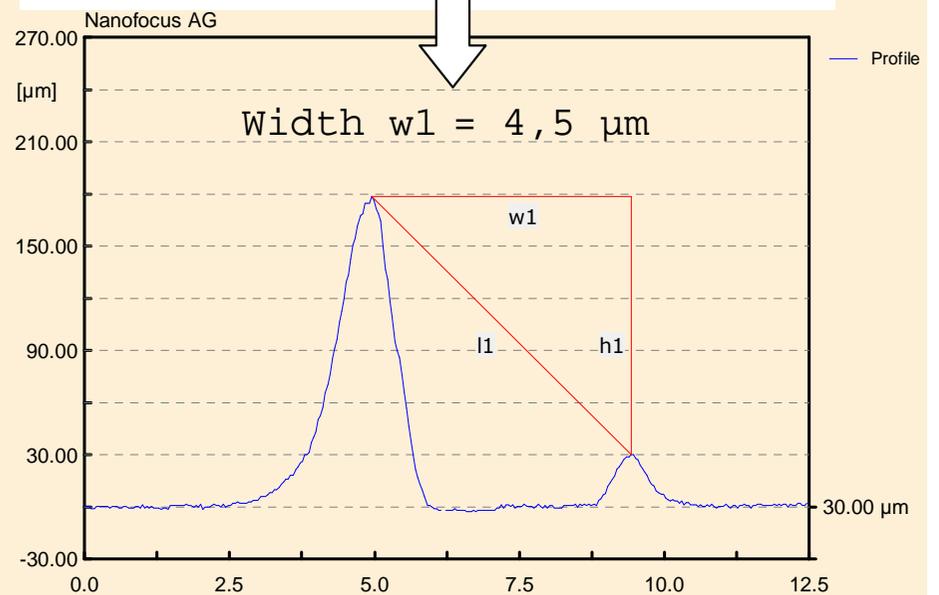
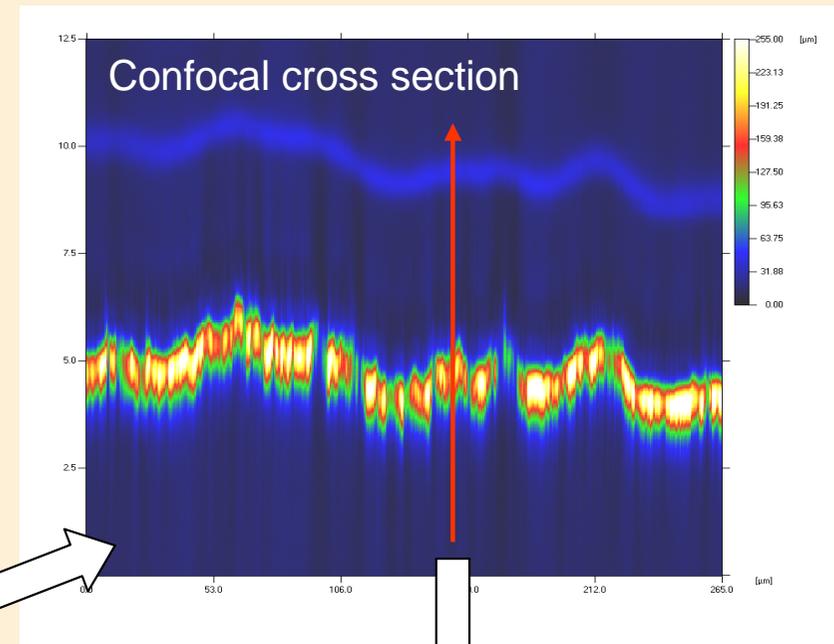
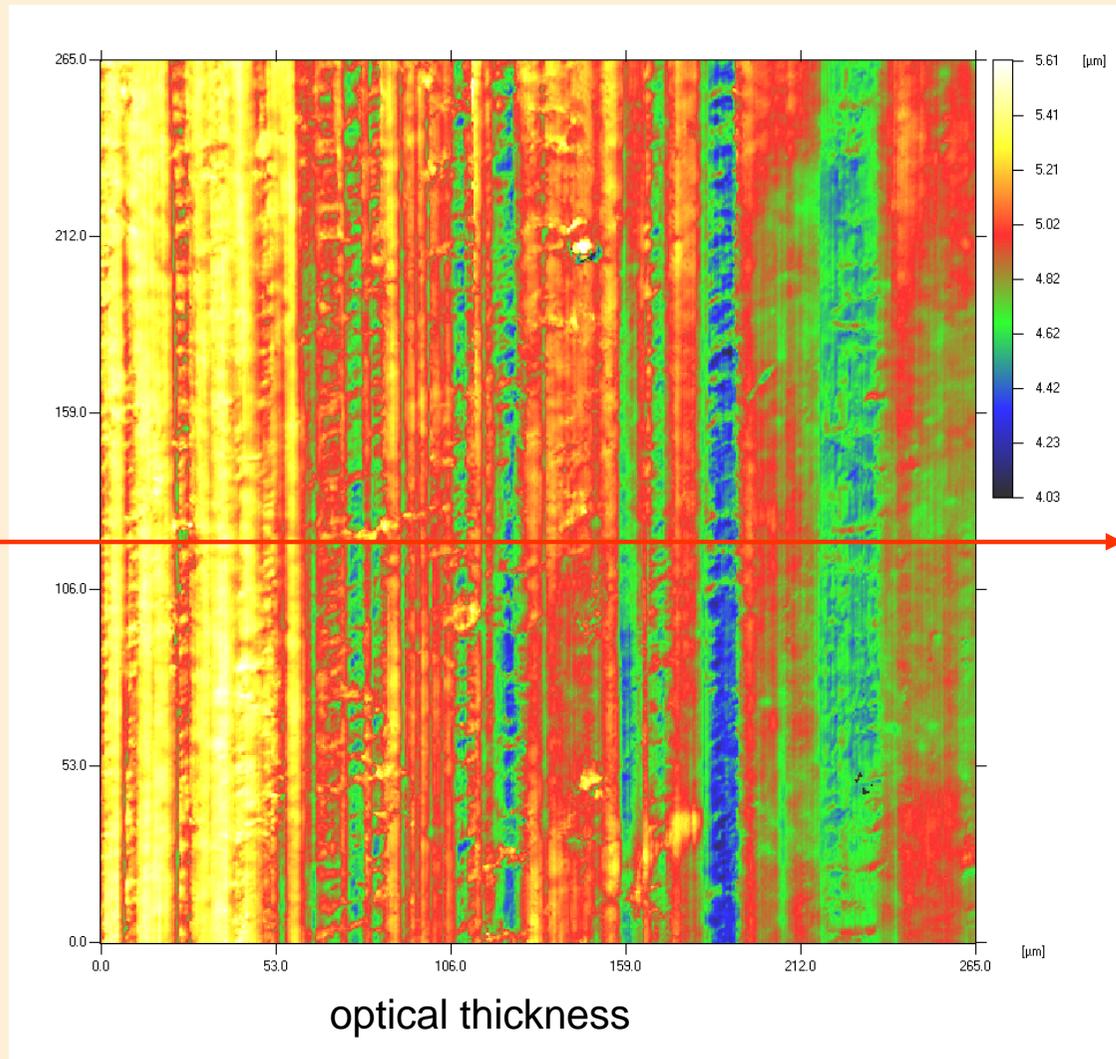


Substrate surface

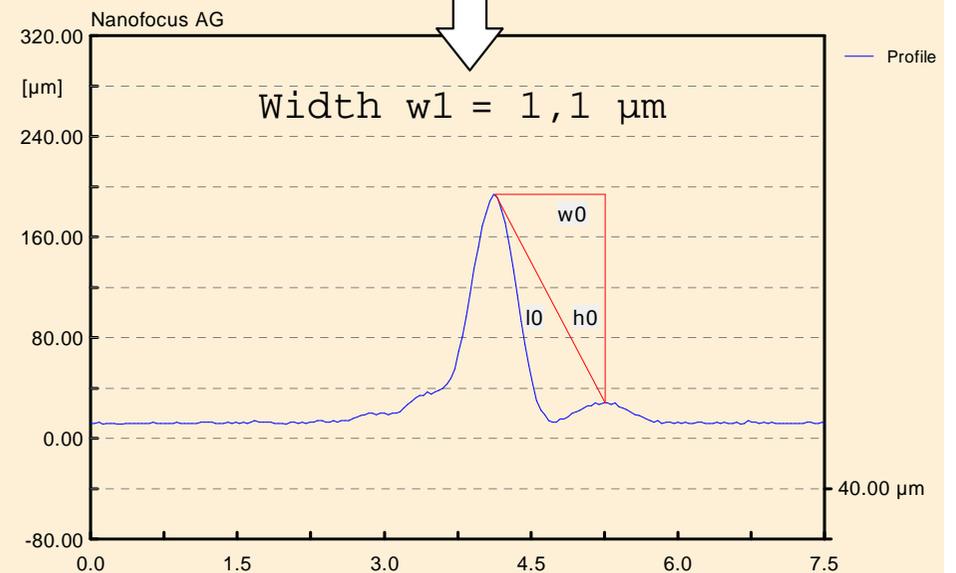
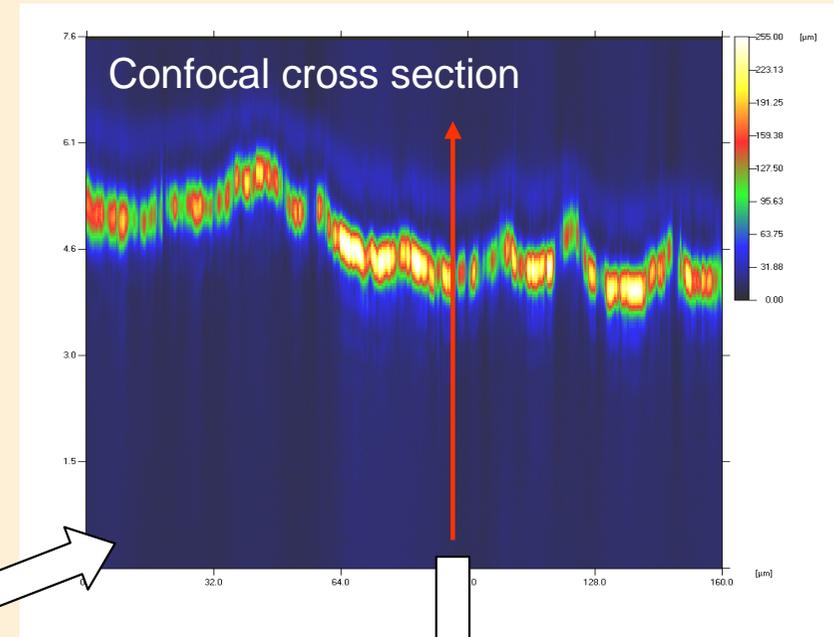
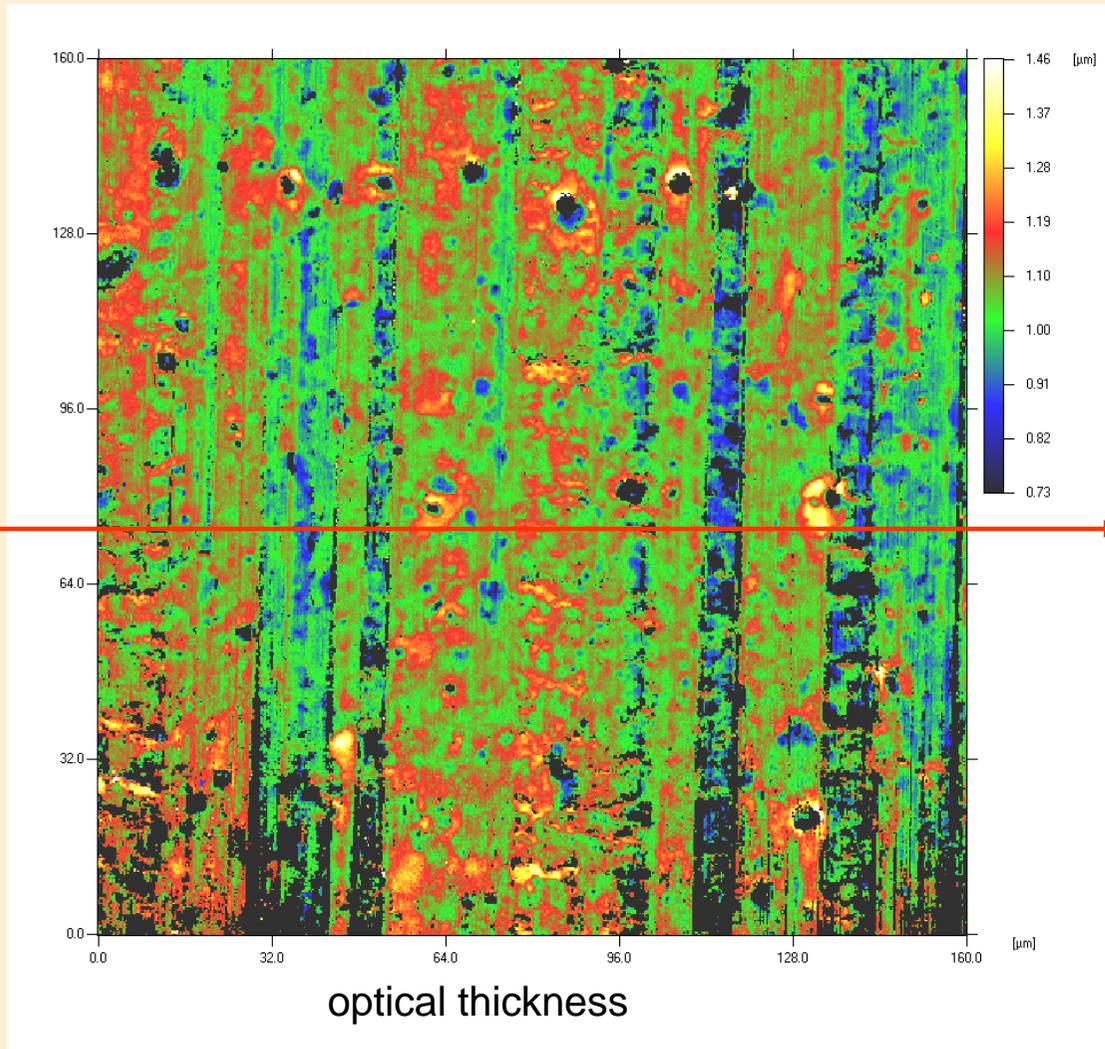
Coating surface

sample#2-260S

Thickness sheet#2



Thickness sheet#4



sample#4-160S

Correlation of topography measurements of NIST SRM 2460 standard bullets by four techniques

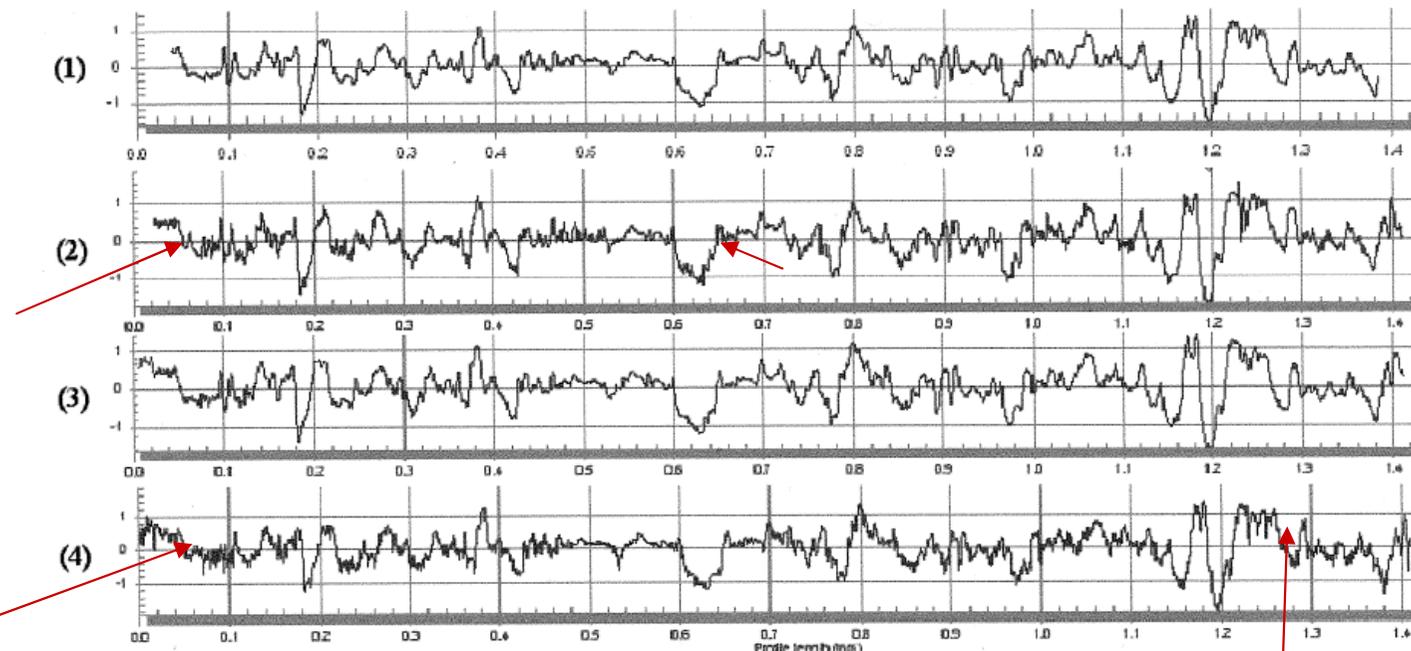
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National Institute of Standards and Technology (NIST) Gaithersburg MD 20899 USA.

¹ Guest Researcher from the Korea Advanced Institute of Science and Technology (KAIST) Daejeon Korea.

² Guest Researcher from the Catholic University of America Washington DC 20064 USA.

B Bachrach and K Bogart
Intelligent Automation Inc. (IAI) Gaithersburg MD 20855 USA.

E-mail: junfeng.song@nist.gov



Stylus
Reference

WLI

NanoFocus
μSurf

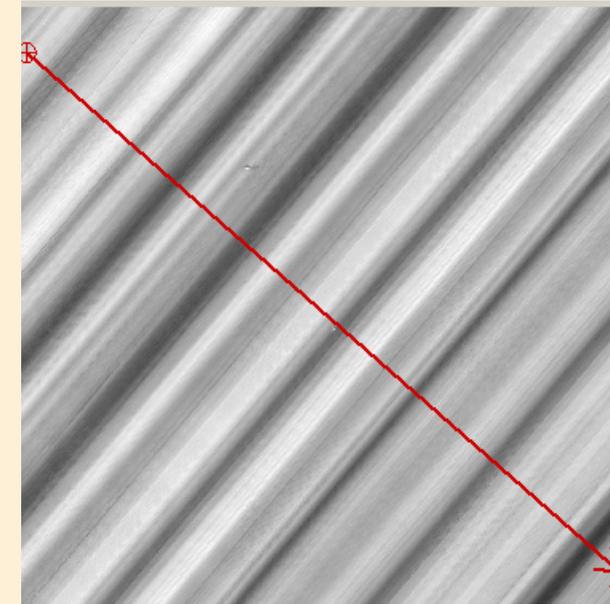
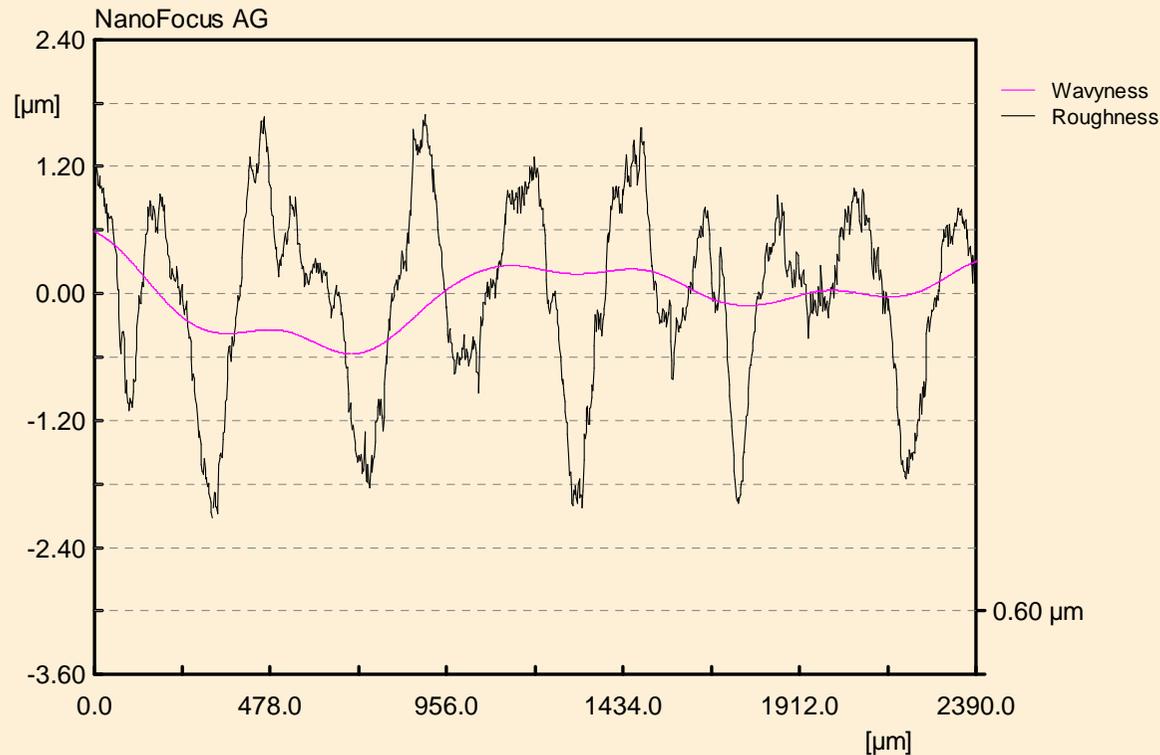
Laser Scanning
Conf. Micr.

Figure 2. The profile of a standard bullet is measured by four techniques. 1) Stylus instrument, $CCF_{max} = 99.6\%$; 2) Interferometric microscope, $CCF_{max} = 92.1\%$; 3) Nipkow disk confocal microscope, $CCF_{max} = 99.0\%$; 4) Laser scanning confocal microscope, $CCF_{max} = 95.3\%$. The vertical unit is μm , the horizontal unit is mm.

Source:

NIST

Roughness Standard



Roughness parameters

Filter = DIN EN ISO 11562

LC (CutOff) = 0,800 mm

Lr = 0,800 mm

NeedleFilter = 0,000 mm

No of Lr N = 3

Not conform with DIN EN ISO 4287

Conform with DIN EN ISO 4288

Ra = 0,680 µm

Rz = 3,498 µm

Rt = 3,822 µm

Rq = 0,857 µm

Rmax = 3,800 µm

Rms S. = 00,053

Wt = 1,159 µm

SEP 1940II(prEN 10049 C=0,5µm)

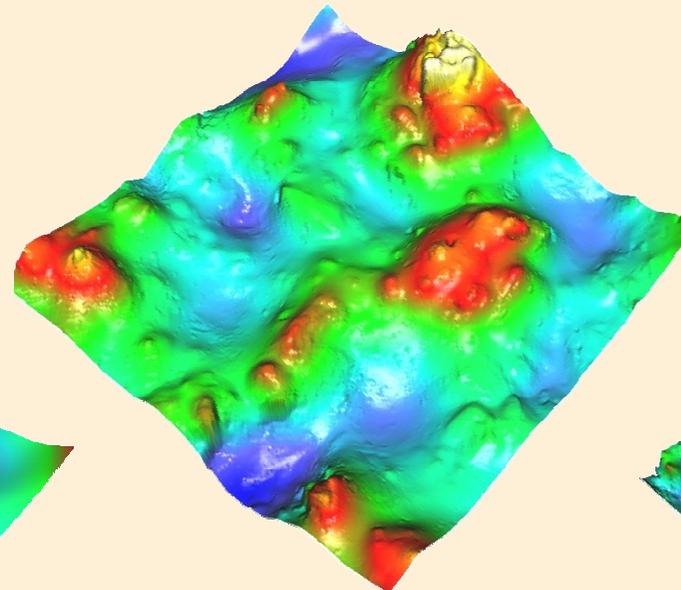
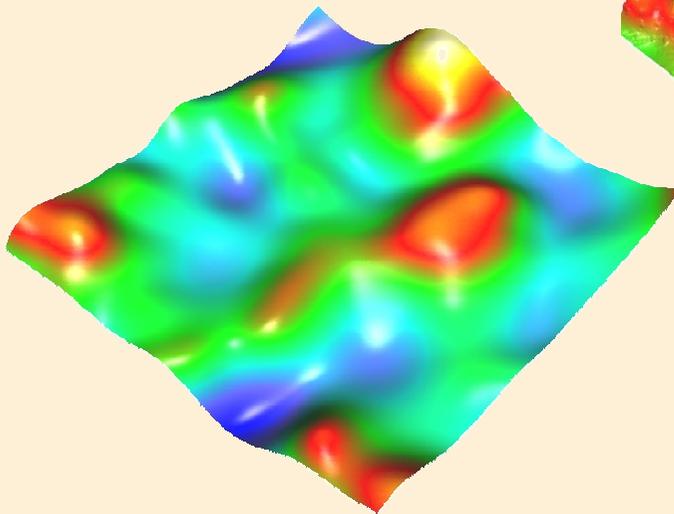
Rpc = 33,369 1/cm

specimen: roughness standard, rotated
lens: 800XS (20x, NA0.6)
area: 2.68 x 2.68 mm²
mode: 3 x 3 stitching, 1370 x 1370 data points
z-stack: 120 frames (2.1s/image)
total acquisition time < 1min

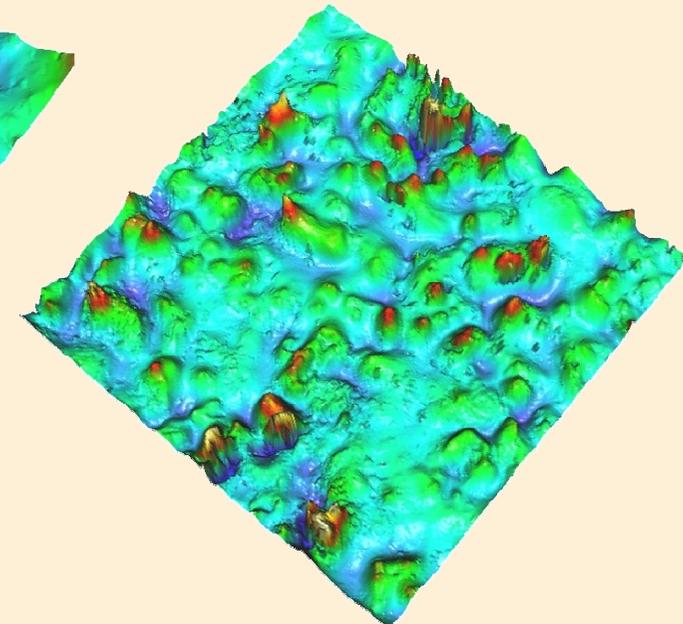
Surface structure consists of amplitudes of different wavelength:

surface raw data

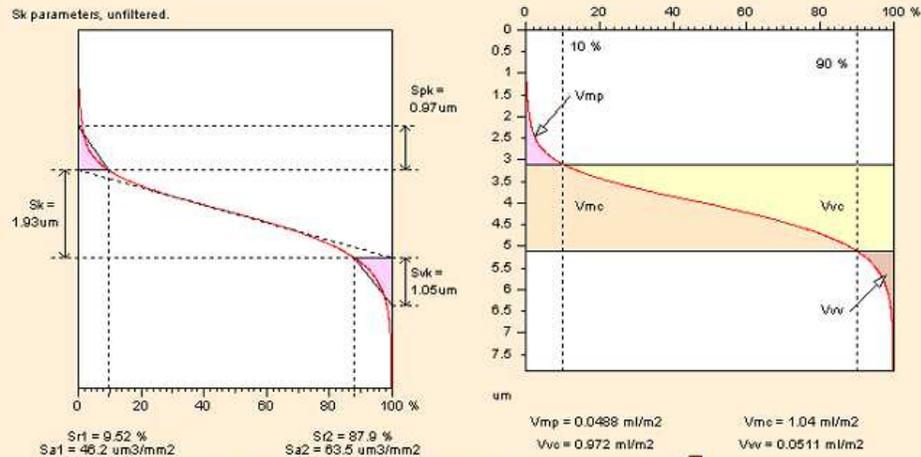
waviness



roughness

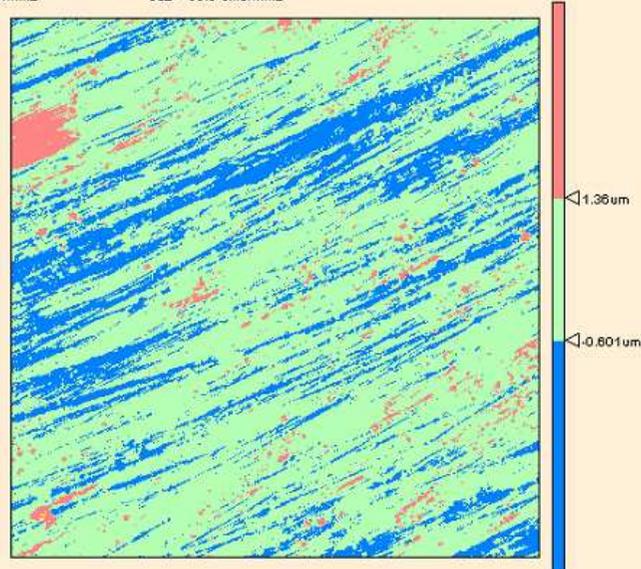


Bearing ratio analysis



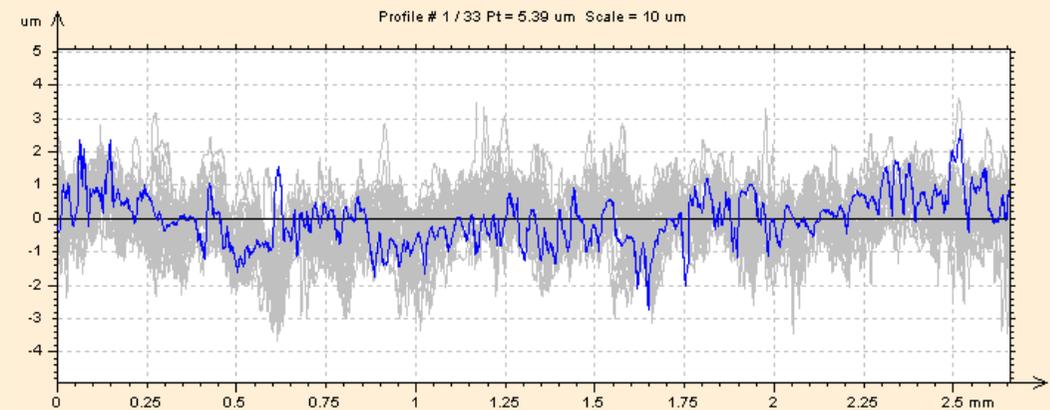
ISO parameters (2D and 3D), functional parameters

ISO 25178			ISO 4287		
Height Parameters			Amplitude parameters - Roughness profile		
Sa	0.642	μm	Ra	0.445	μm <small>Ra: Arithmetic Mean Deviation of the roughness profile.</small>
Sq	0.843	μm	Rq	0.569	μm <small>Rq: Root-Mean-Square (RMS) Deviation of the roughness profile.</small>
Ssk	-0.0508		Rsk	-0.177	
Sku	4.27		Rt	4.23	μm <small>Rt: Total Height of roughness profile.</small>
Sp	4.07	μm	Rz	2.93	μm <small>Rz: Maximum Height of roughness profile.</small>
Sv	3.81	μm	Material Ratio parameters - Roughness profile		
Sz	7.88	μm	Rmr	5.27	% <small>Rmr: Relative Material Ratio of the roughness profile.</small>
			Rdc	0.918	μm <small>Rdc: roughness profile Section Height difference</small>



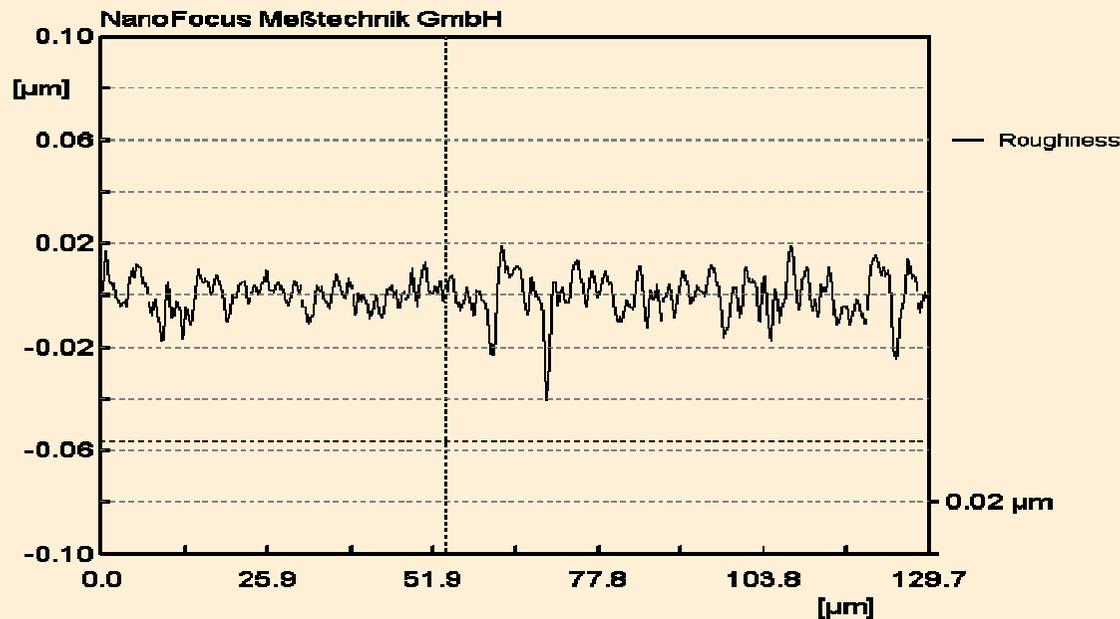
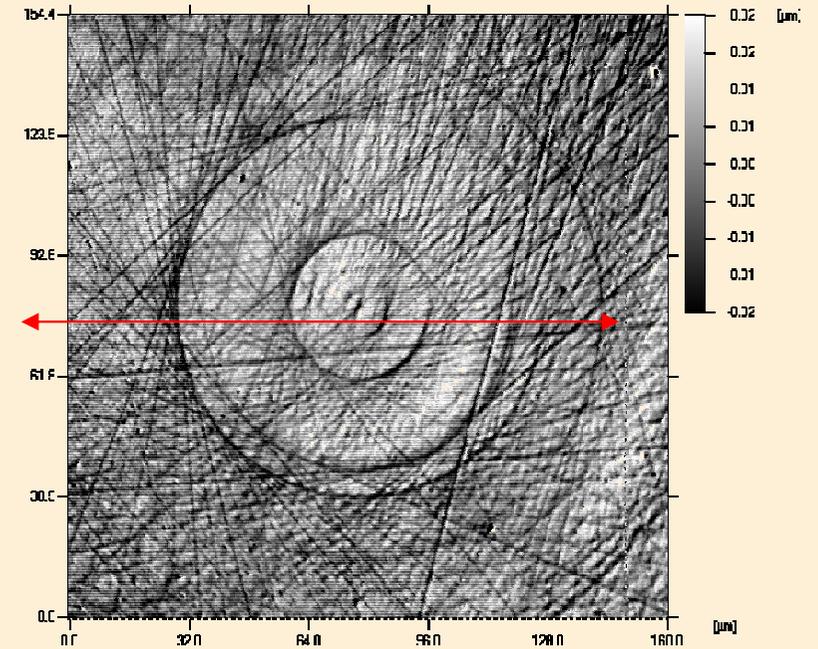
	■	■	■
Projected Area (%)	21.5	74.4	4.18
Volume of void (%)	3.87	64.5	99.1
Volume of material (%)	96.3	35.5	0.862

Advanced profile analysis



Wafer Backside Grinding

Confocal System μ Surf 100x optics

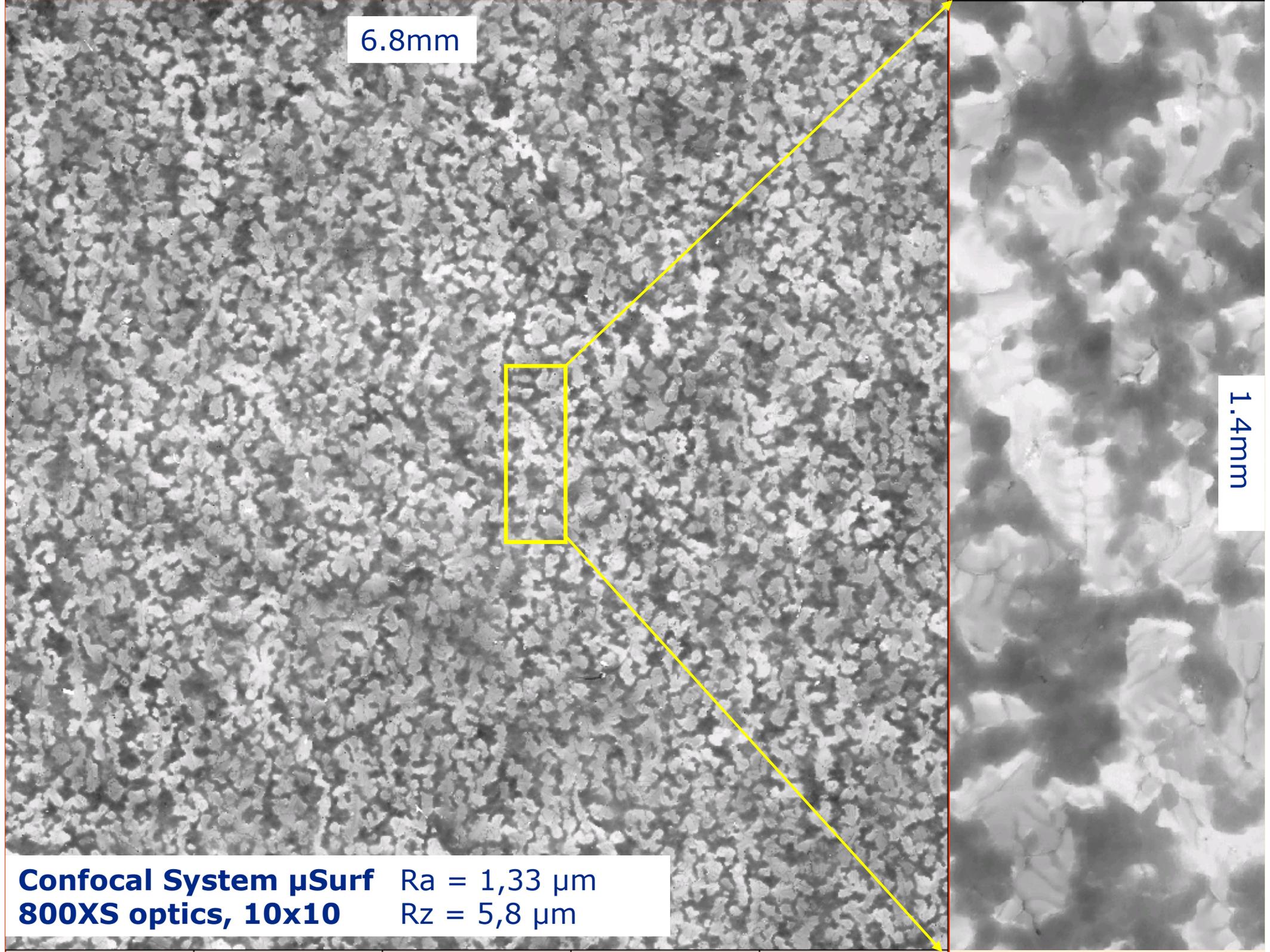


$R_a = 0.005 \mu\text{m}$
 $R_z = 0.038 \mu\text{m}$

6.8mm

1.4mm

Confocal System μ Surf Ra = 1,33 μ m
800XS optics, 10x10 Rz = 5,8 μ m



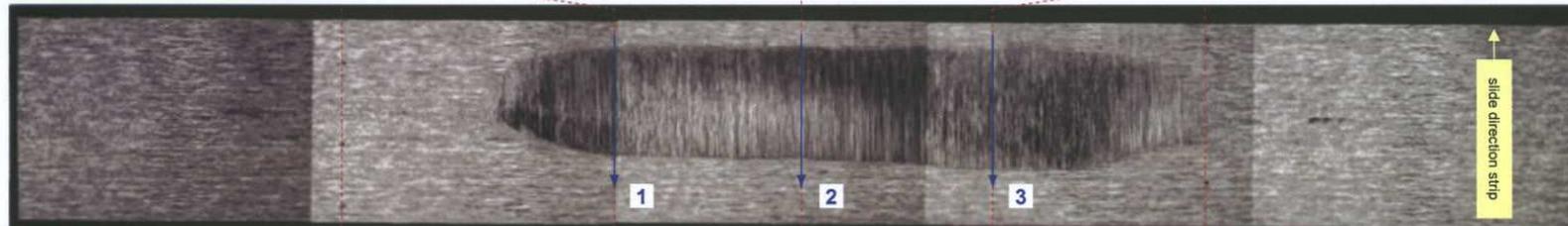
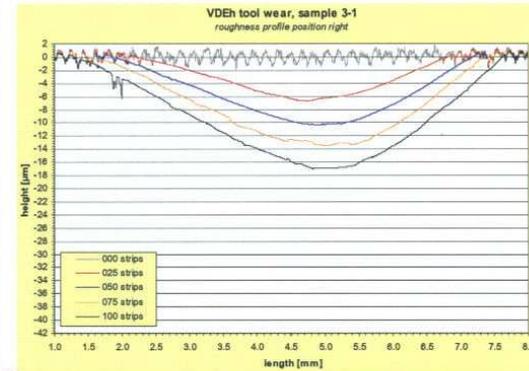
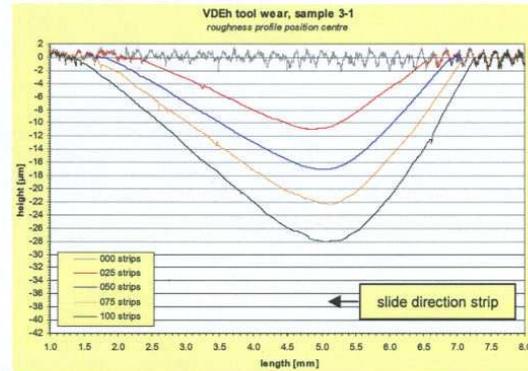
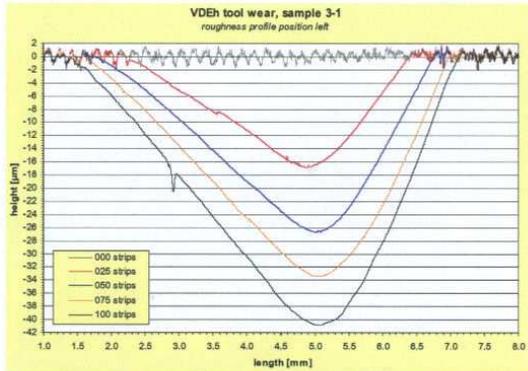
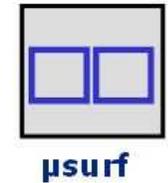
Wear Test



VDEh tool wear roughness investigation VDEh 3_1: strip EZ DC05 + GPTH9491 (PACcode: 20050131)

Appelman
Landskroon

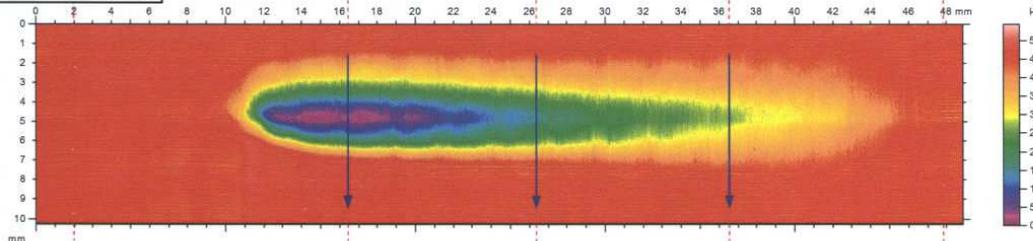
mobile



preview video
camera

Pt-waarde [µm]	VDEh 3_1				
# strips	0	25	50	75	100
lineprofiel 1	2.2	16.9	26.8	33.5	40.8
lineprofiel 2	2.3	11.0	17.1	22.4	28.1
lineprofiel 3	2.0	6.8	10.4	13.5	17.0
average	2.2	11.6	18.1	23.1	28.6
stdev	0.2	5.1	8.3	10.0	11.9

VDEh 3_1		Initiele ruwheid
λ_c : 0.8 mm (n=6)		gem. stdev
Ra	[µm]	0.50 0.09
Rsk		-0.25 0.08
RPc(±0.5)	[pks/cm]	6.49 0.85
Rz	[µm]	3.00 0.11
Rp	[µm]	1.32 0.07
Rv	[µm]	1.68 0.06



Materials and Surface Analysis

MSAnr.: 2070388



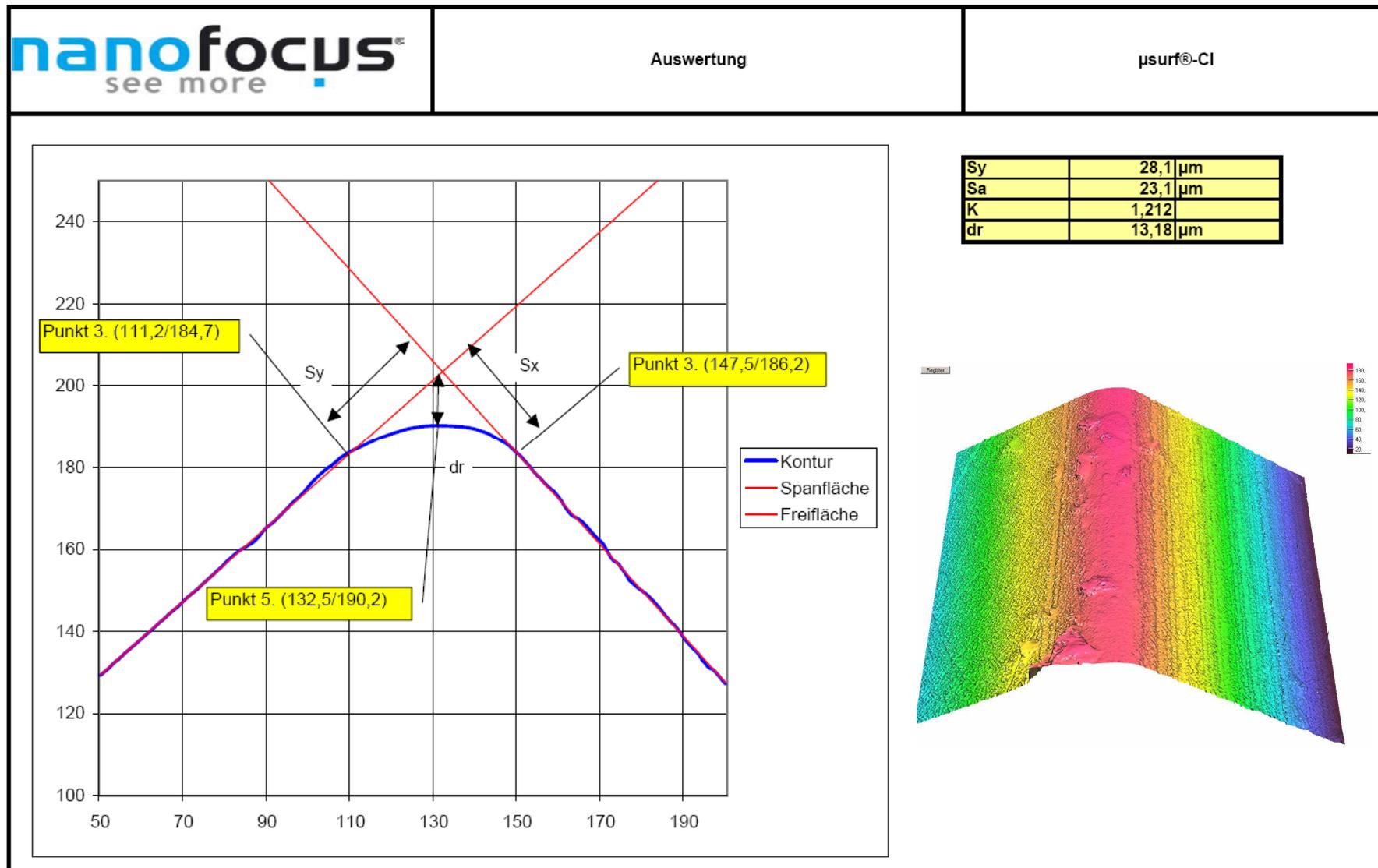
lens: 3200S (5x)
area: 10 x 50 mm²
18x4 stitching



3rd European Fuchs Symposium
18./19.Jun.2007

Tool wear in pressing of zinc-plated and coated steel sheets
Werkzeugverschleiß bei der Umformung von verzinktem und beschichtetem Stahlblech
Chiel Dane, Corus Research Development & Technology

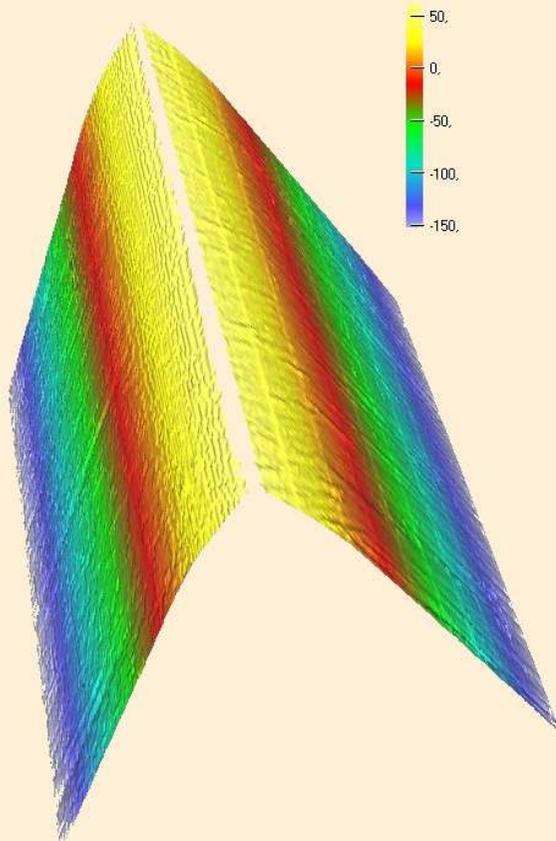
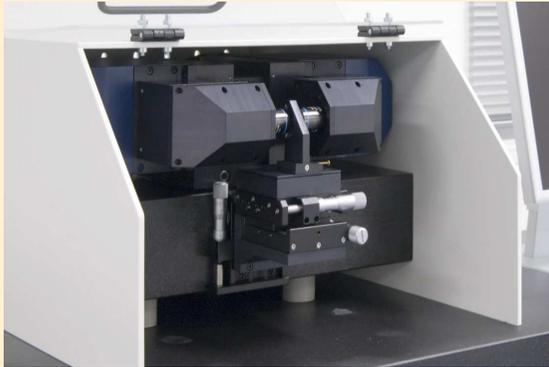
Evaluation: tool wear



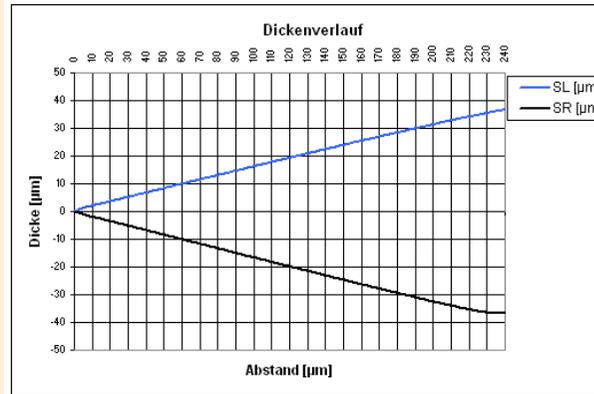
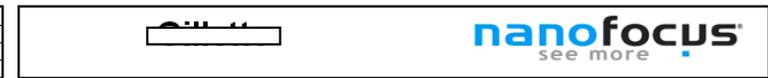
Auswertung mit NF-ActiveX-Modul (Kantenverschleiss)

(Mittelung über mittleren Bildbereich (geringer verschmutzter Bereich))

Blade Inspection



System	µSurf TW111 320	Datum	29.01.2007
Benutzer	Marcus Grigat	Uhrzeit	15:40:22
Probe	Probe 4		
Beschreibung			

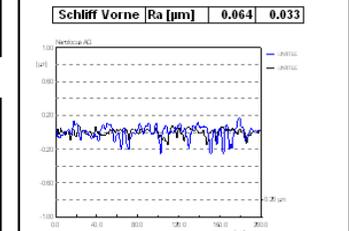
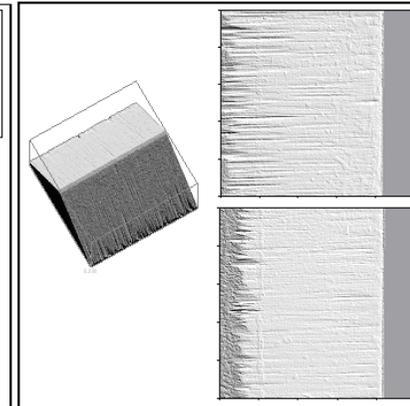
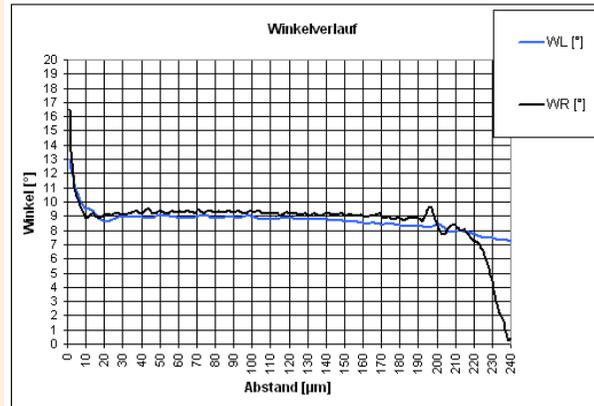
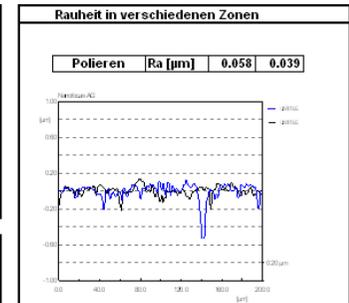


Spitzengeometrie

x [µm]	D [µm]	SL [µm]	SR [µm]	Delta [µm]	WL [°]	WR [°]
0	0.00	0.00	0.00	0.00		
1	0.69	0.60	0.77	-0.09	12.97	16.50
2	1.13	1.02	1.24	-0.11	12.35	13.59
3	1.55	1.45	1.66	-0.10	11.80	11.97
4	1.96	1.86	2.05	-0.09	11.27	10.99
5	2.32	2.23	2.41	-0.09	10.84	10.41
6	2.68	2.60	2.77	-0.09	10.42	10.08
7	3.04	2.96	3.12	-0.08	10.08	9.78
8	3.37	3.30	3.45	-0.08	9.85	9.45
9	3.70	3.64	3.77	-0.07	9.62	9.12
10	4.02	3.96	4.08	-0.06	9.55	8.89

Facettenauswertung

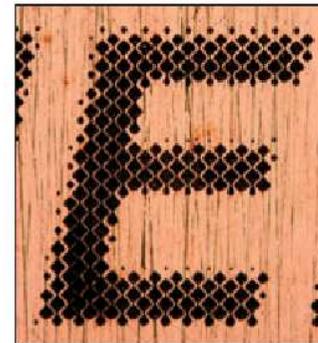
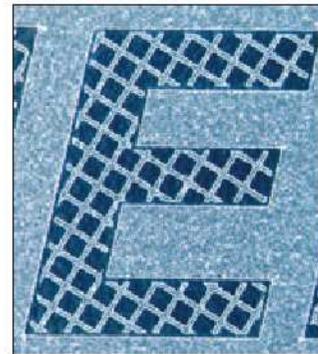
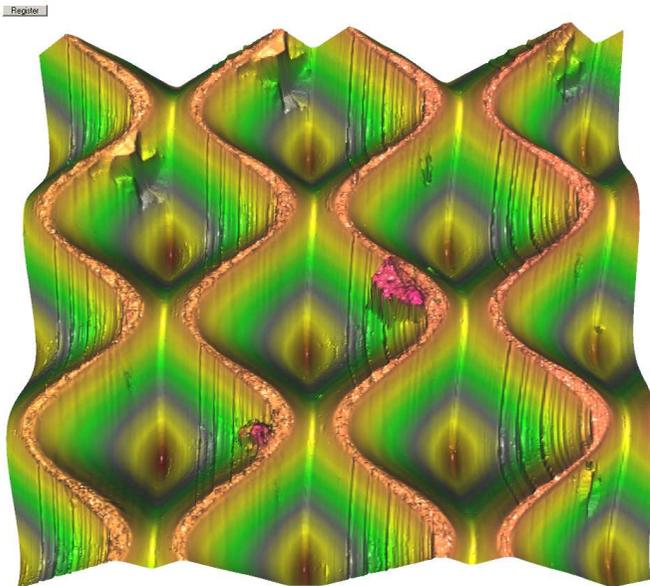
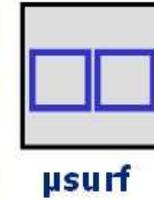
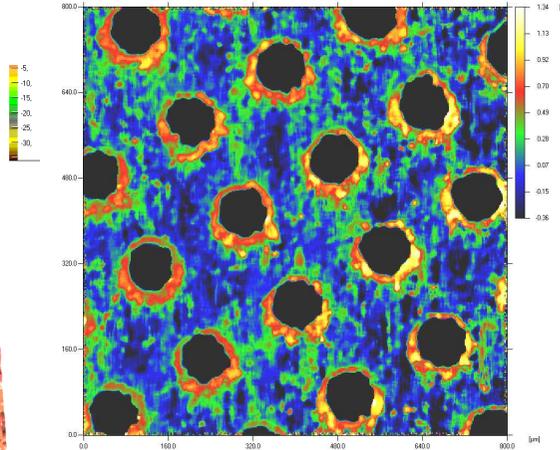
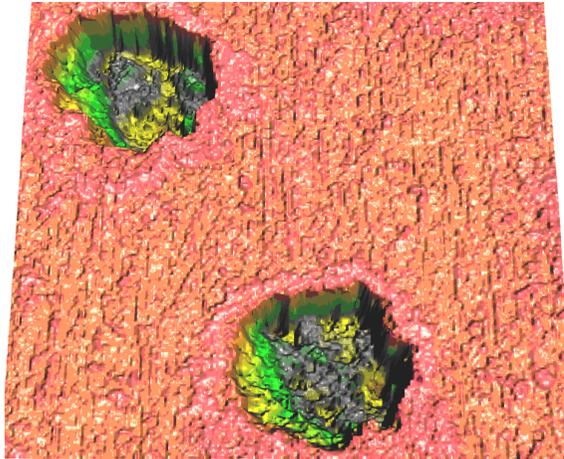
	WL [°]	WR [°]	Delta [°]
Schliff	8.86	9.23	-0.37
Polieren	13.6	9.1	4.57
Schliff	162.6	181.3	-18.77



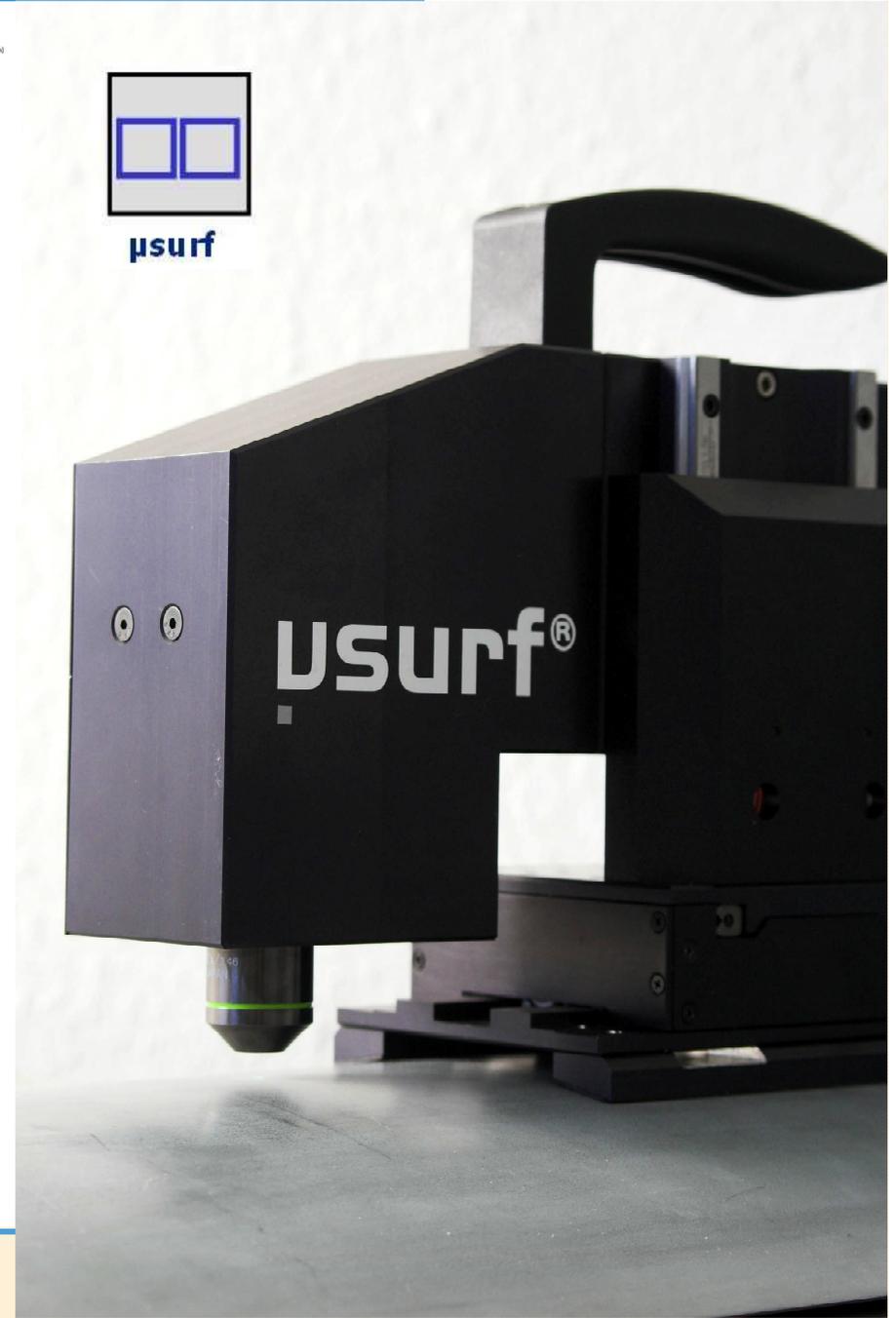
- recording of both sides without moving the sample
- auto calibration enables absolute thickness measurement
- geometry, symmetry, roughness
- non contact

Printing Cylinders

Laser (800S, Zoom)

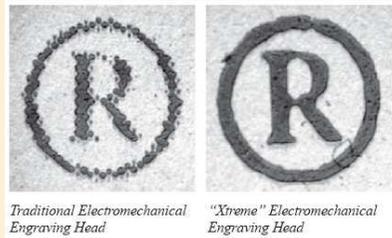
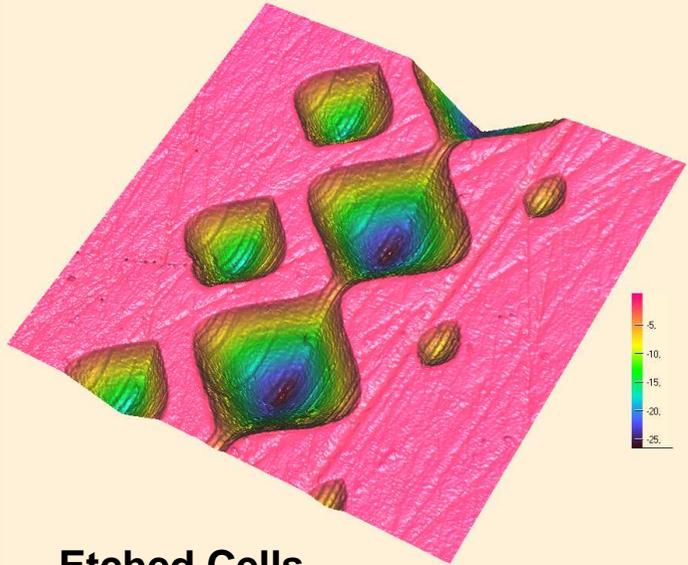


Stylus (320S)

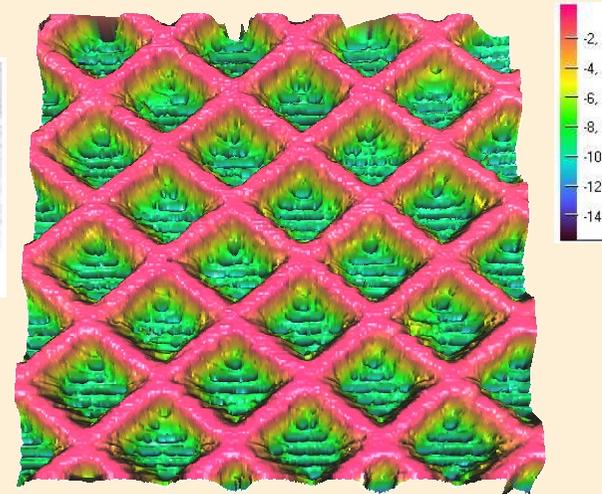


Gravure - Examples

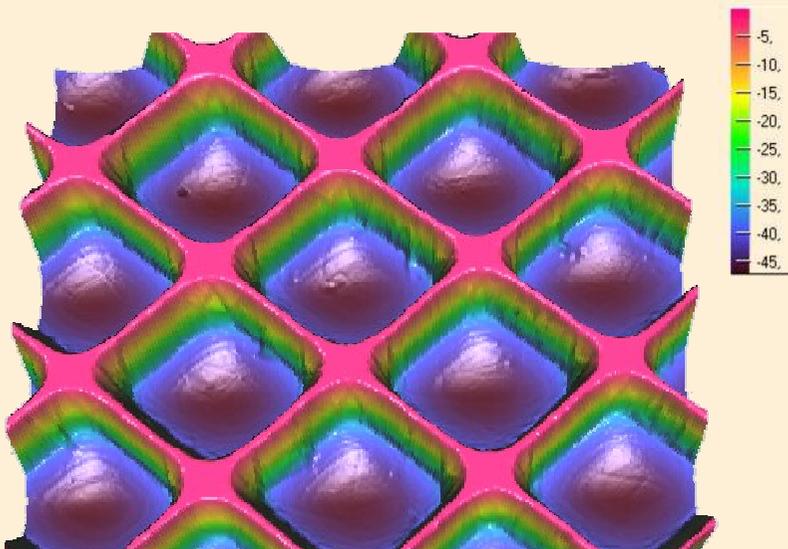
Electromechanical Gravure



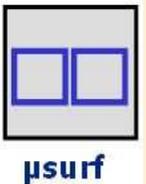
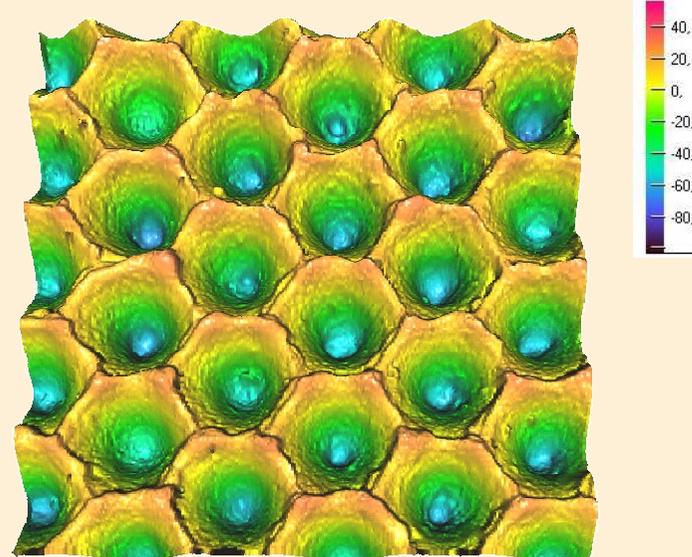
Extreme Gravure



Etched Cells



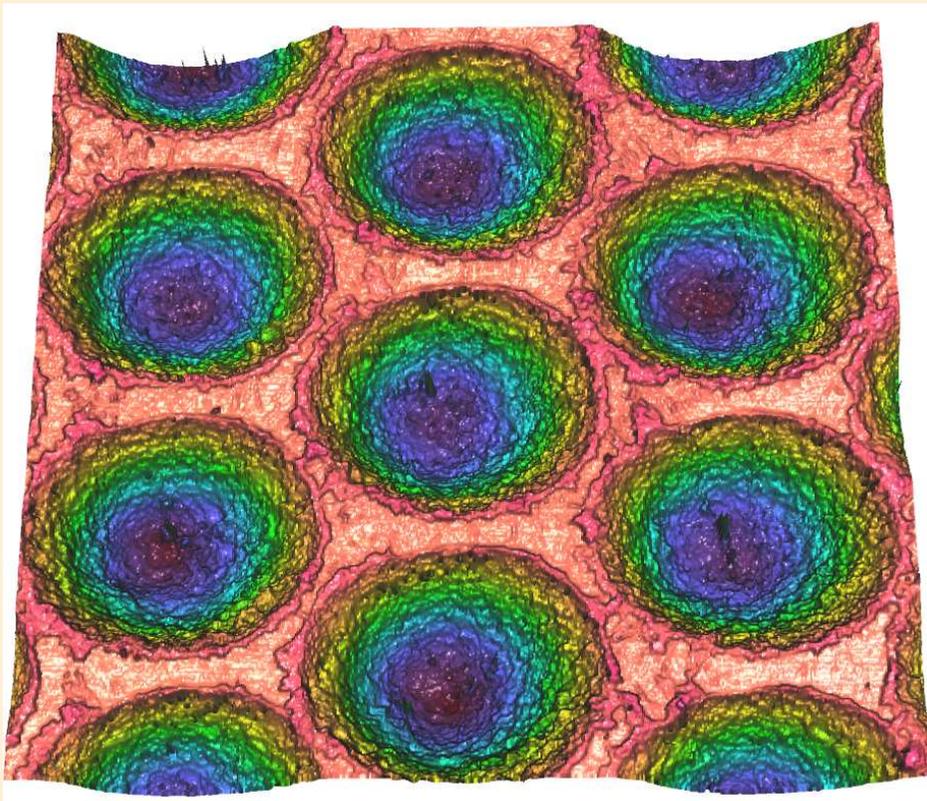
Anilox



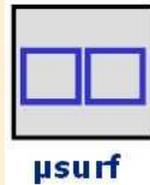
μsurf

Gravure on Printing Roll

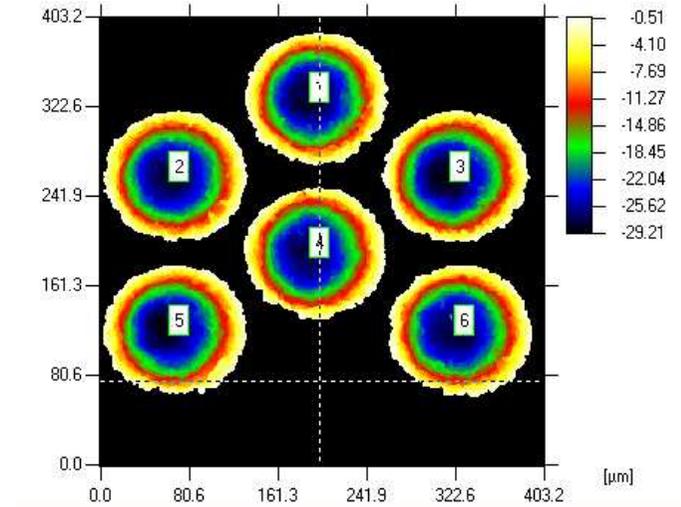
Laser Gravure 320S



1. Measurement

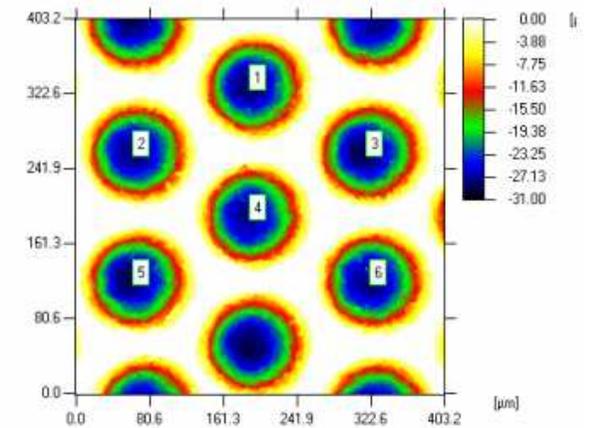


2. Segmentation



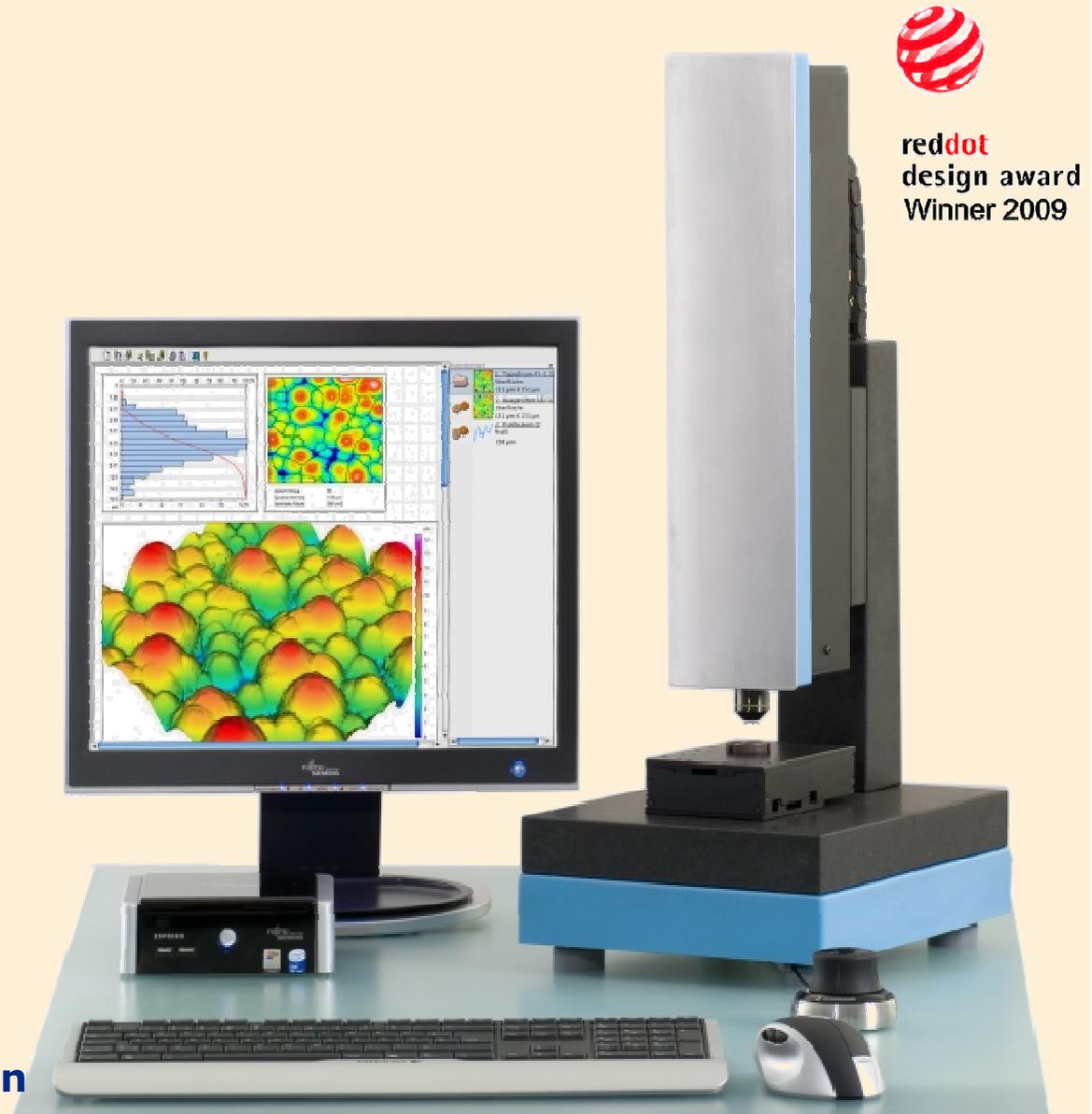
3. Report Sheet

Raster	74,94				
Fläche	11944,1	μm^2			
Tiefe	28,60	μm			
Volumen	9,59	ml/m^2			
Breite	130,47	μm	Länge	117,58	μm



μsurf explorer

- **robust design**
- **high precision**
 - **high resolution**
 - **large flank angles**
 - **high dynamic range**
- **fast area measurement**
- **non-contact**
- **symmetric, optimized light path**
- **simple operation**
- **flexible software package**
- **x, y, z motorized**
- + **LED light source**
- + **compact MPD**
- + **internal controller w. USB interface**
- **limited in sample size and automation**



μsurf Workplace with MP 500



- large gantry with**
- 300mm x 300mm stages
 - vacuum chuck
 - active vibration isolation
 - offset camera
 - SC1000 controller

NanoFocus Customers (Automotive)



NanoFocus Customers (Electronics, Hybrid)

